

Multi-Gbps Optical Receivers with CMOS Integrated Photodetectors

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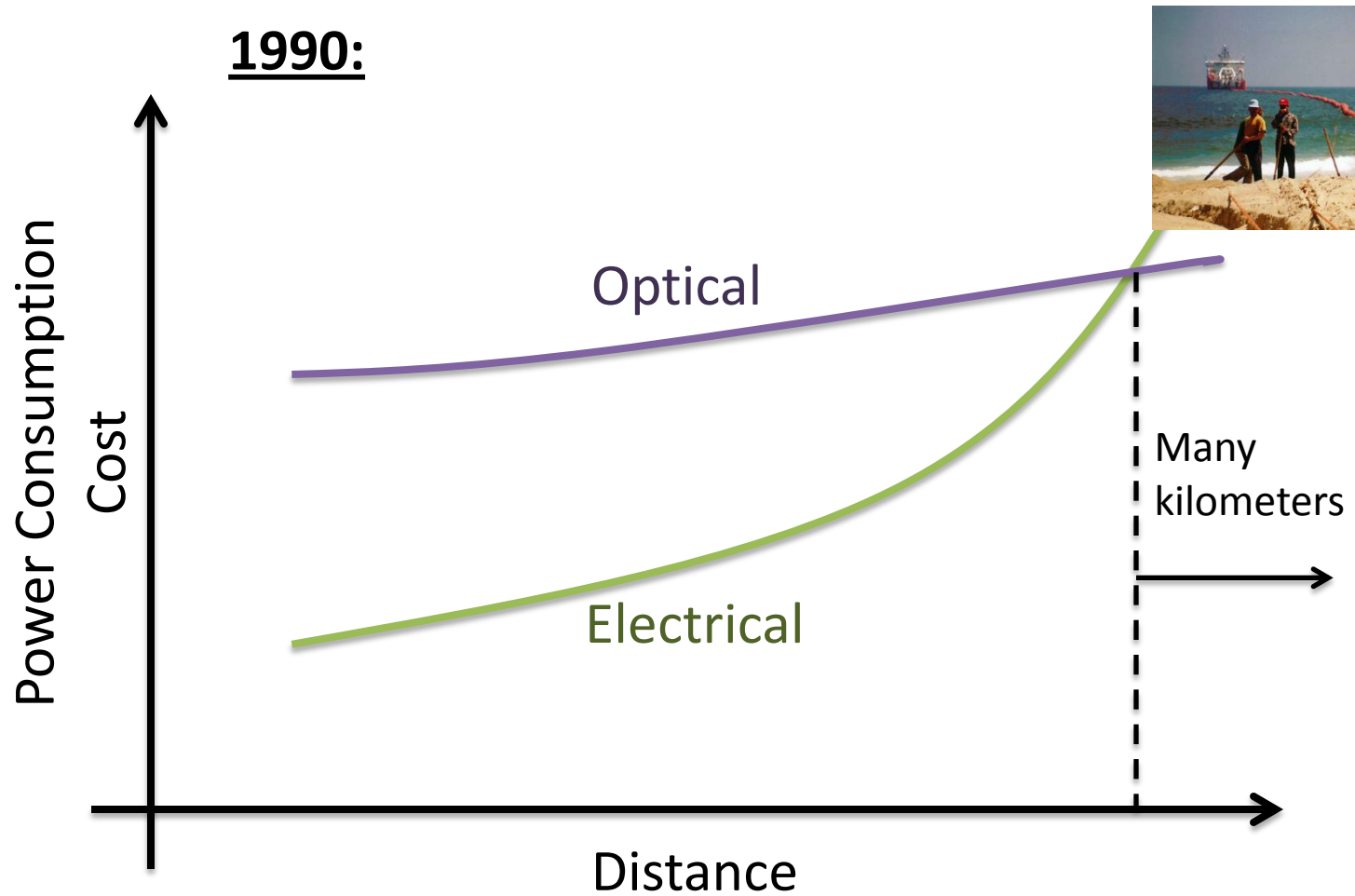
Email: tony.chan.carusone@isl.utoronto.ca

February 2, 2011

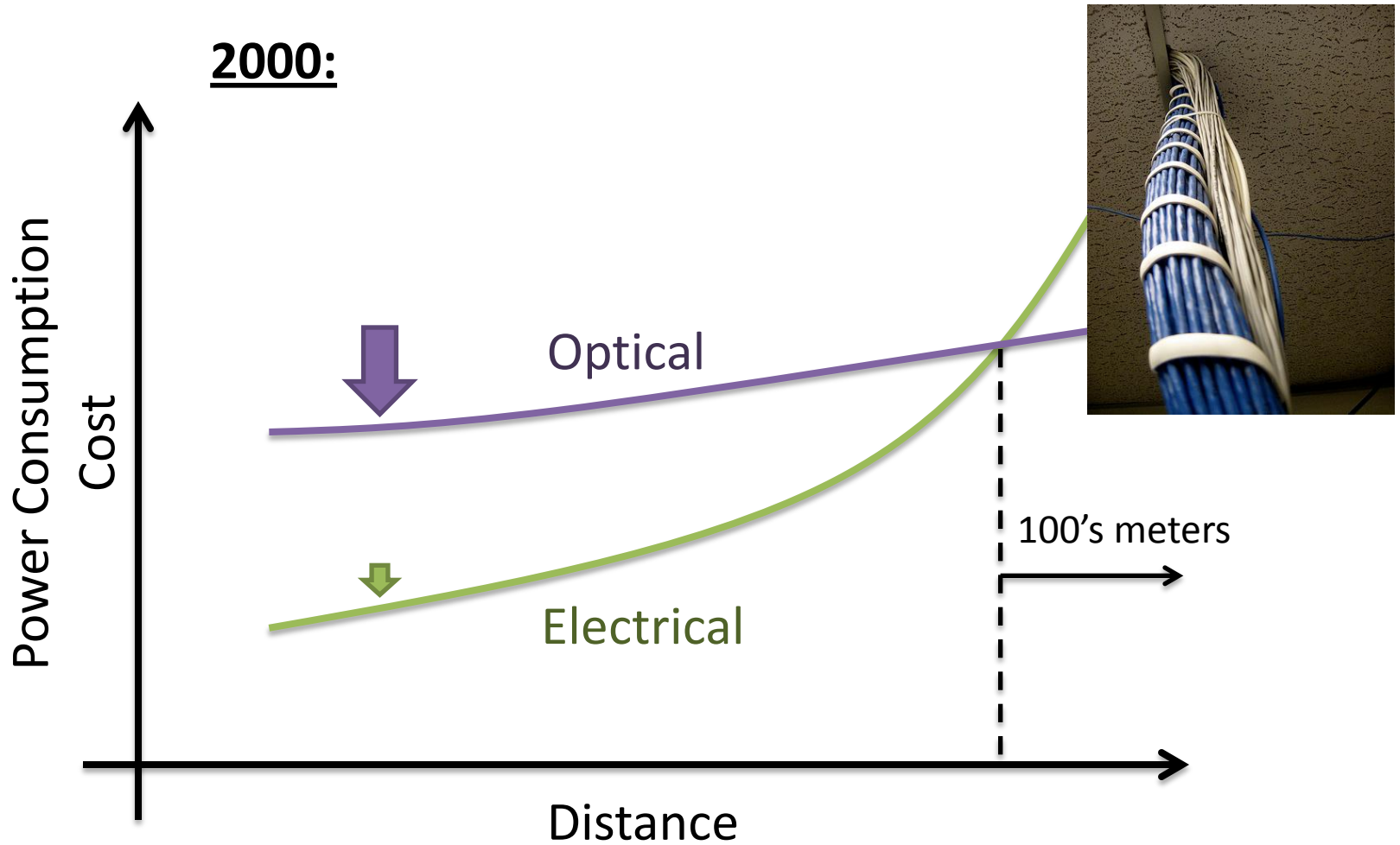
Outline

- **Introduction**
 - **Trend towards short-reach optical**
 - **Trend towards highly integrated transceivers**
- Tutorial on High-speed CMOS photodetection
 - Optical properties of silicon
 - Standard CMOS photodetectors
 - Diffusion-shielded photodetectors
 - Spatially modulated light detectors
- Equalization to improve CMOS photodetectors
 - Analog equalization
 - Decision-Feedback Equalization
- Case study: 0.18 μm CMOS integrated optical receiver
 - SML detector
 - Analog equalizer
- Photodetectors in nanoscale CMOS technologies
 - Experimental results from a 65 nm process

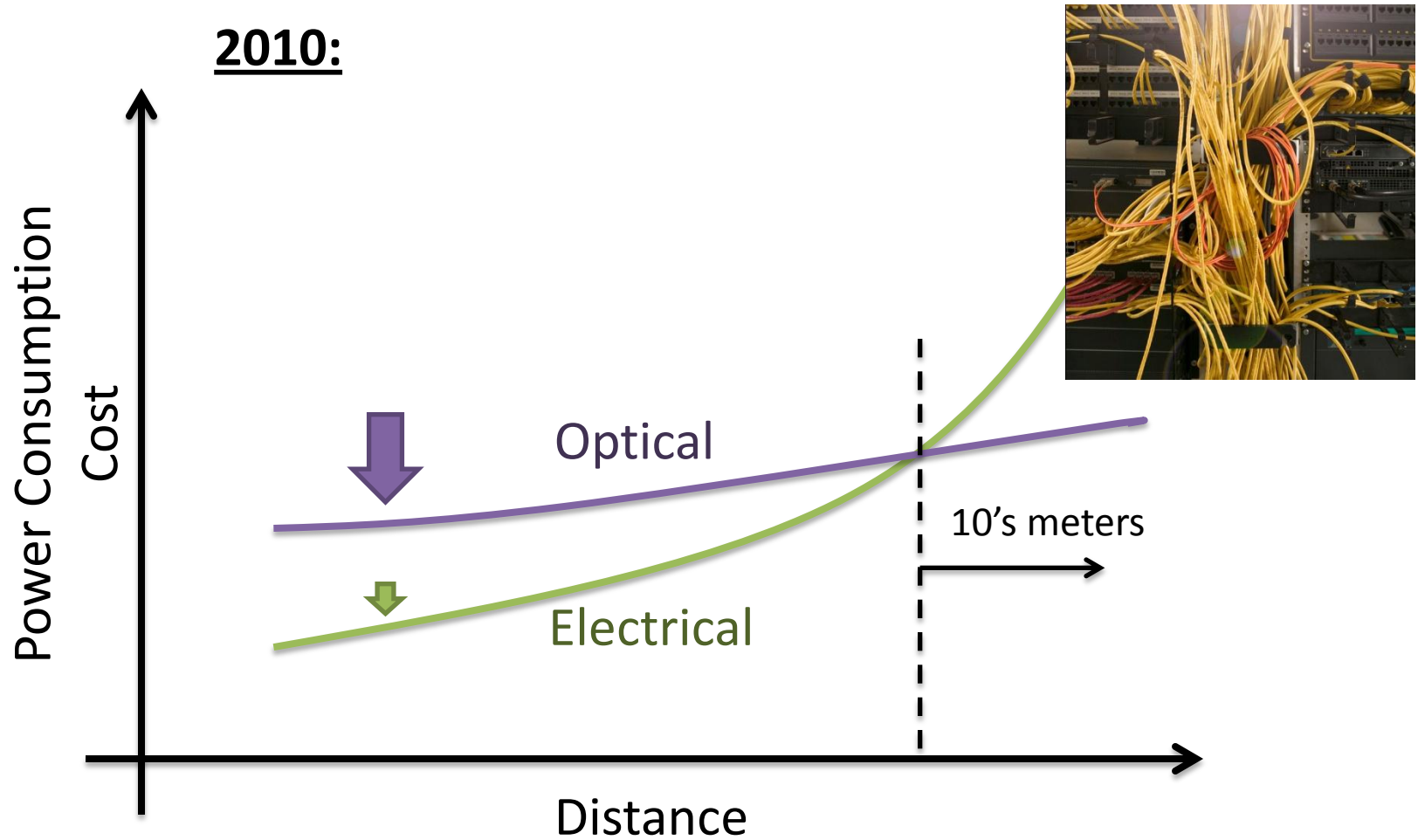
Optical Communication Evolution



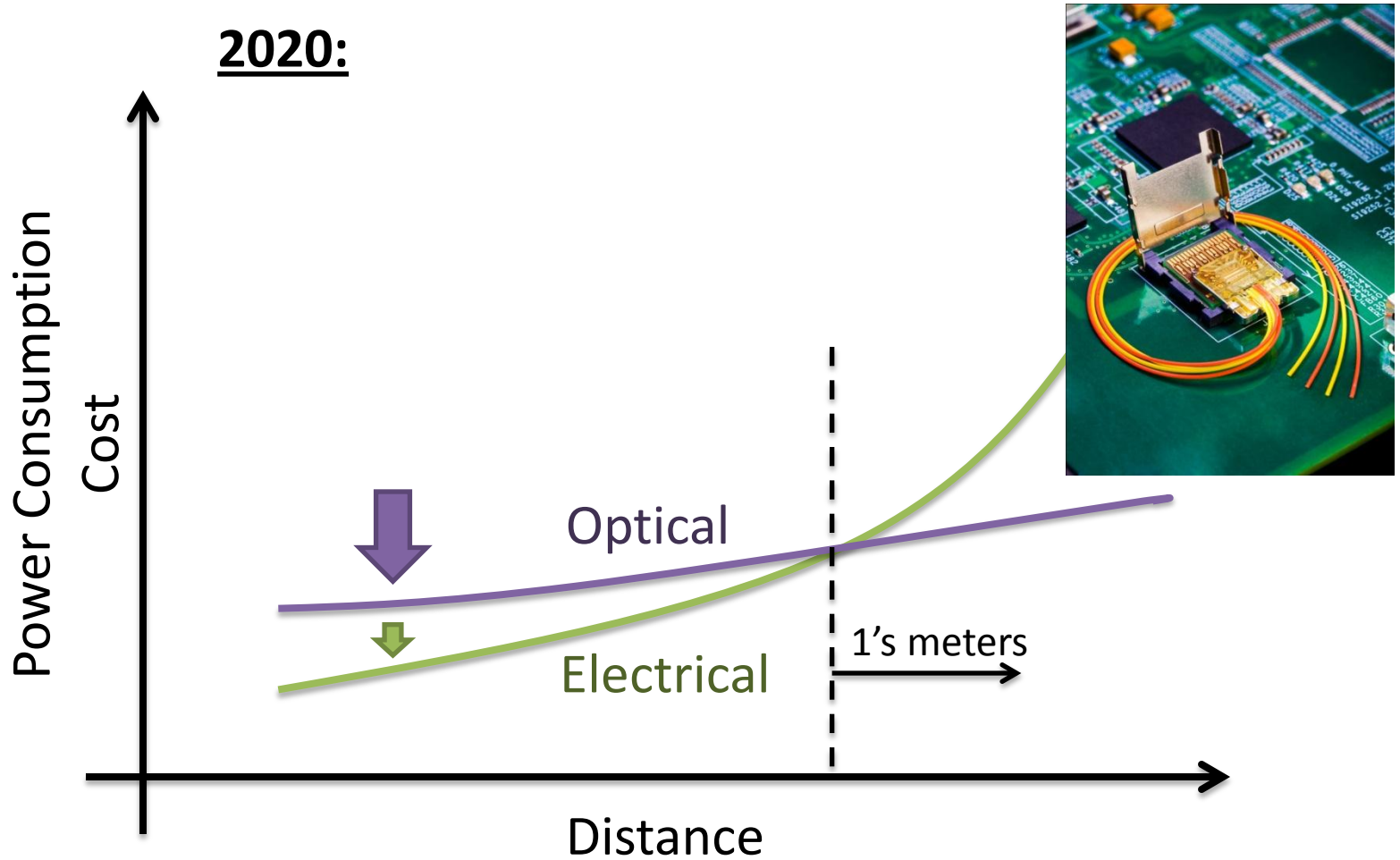
Optical Communication Evolution



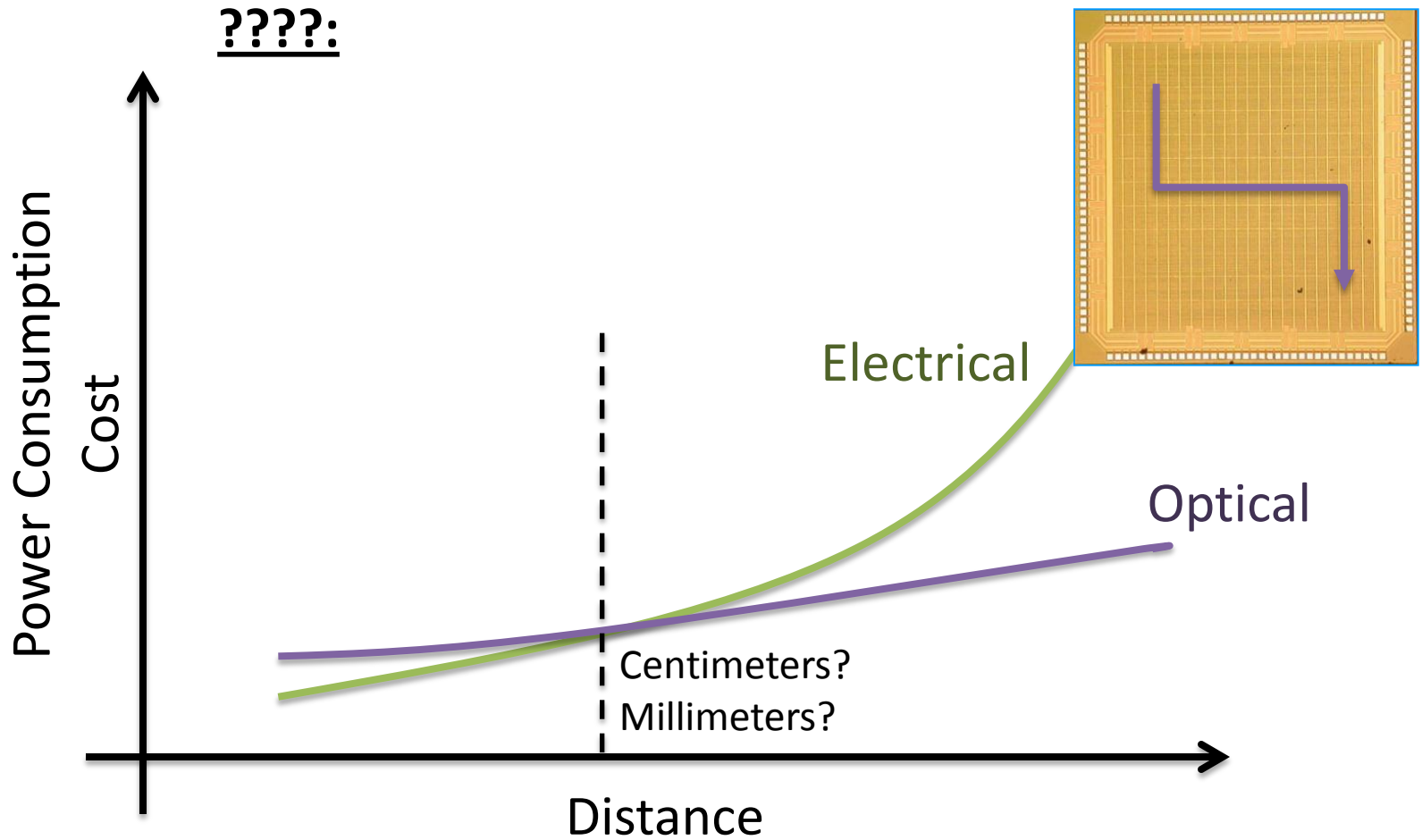
Optical Communication Evolution



Optical Communication Evolution



Optical Communication Evolution



Short-Reach Optical Communication



Characteristics

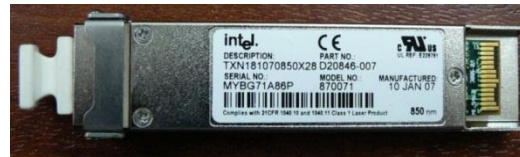
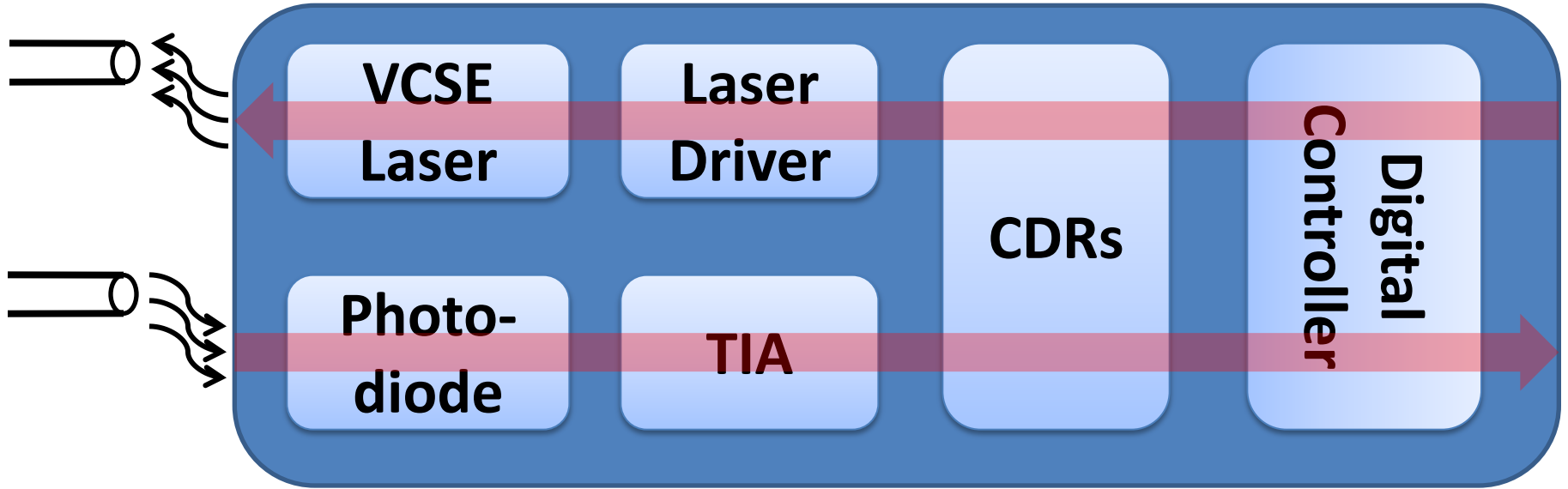
- High volume
- High port density

Requirements

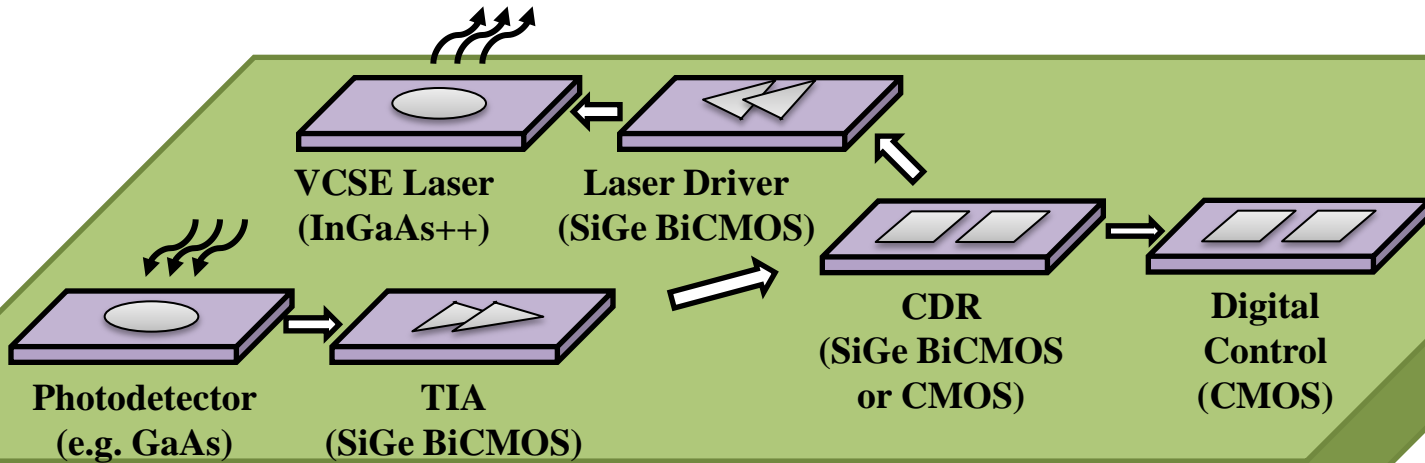
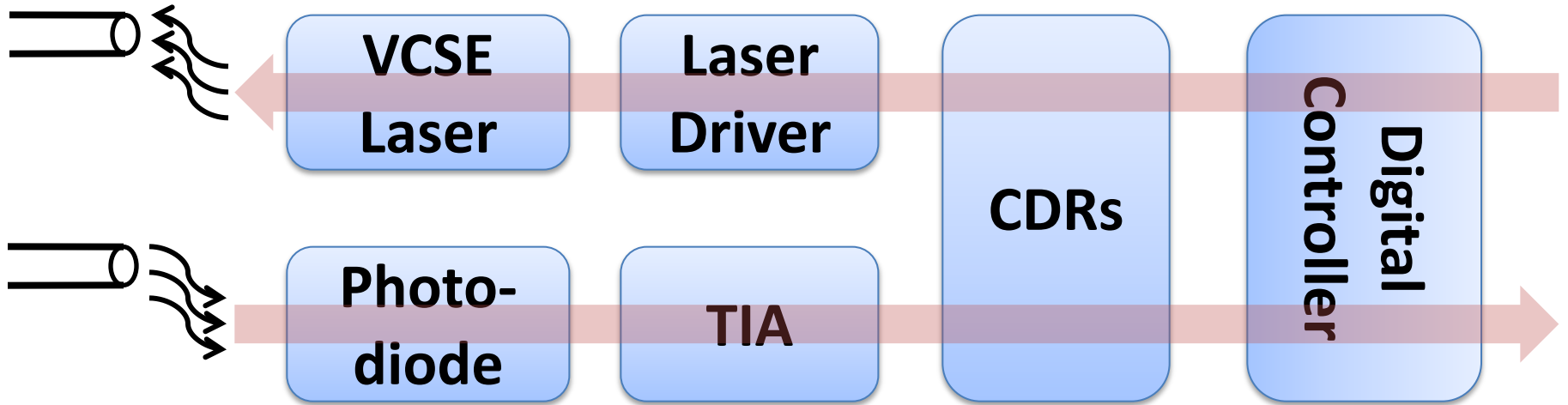
- CHEAP!
 - VCSEL lasers at $\lambda = 850\text{nm}$
 - Multimode fiber
- Integration
- Low-power

Good recipe for CMOS!

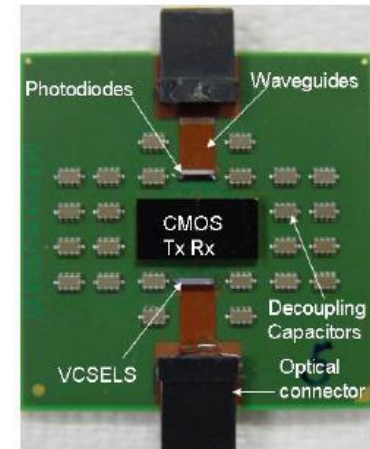
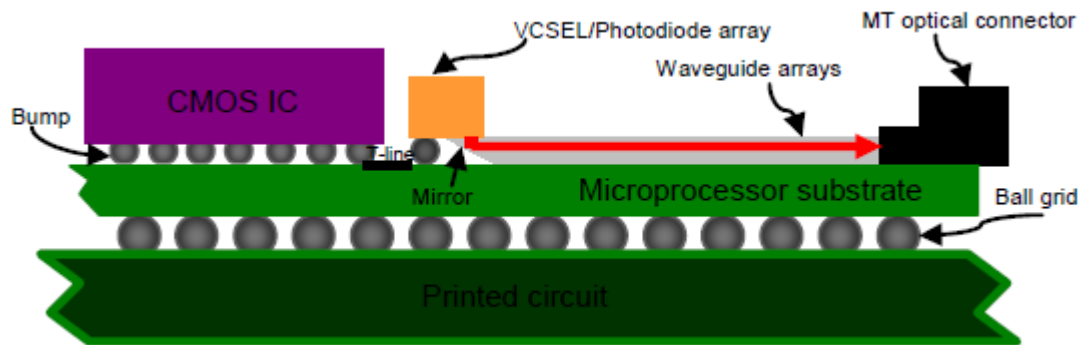
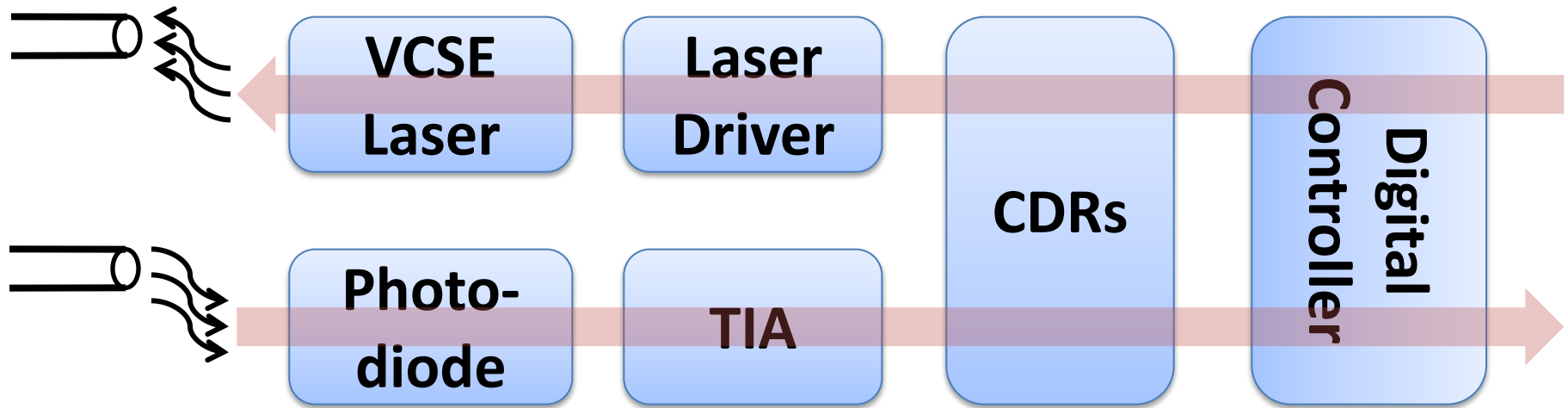
Optical Transceiver



Optical Transceiver

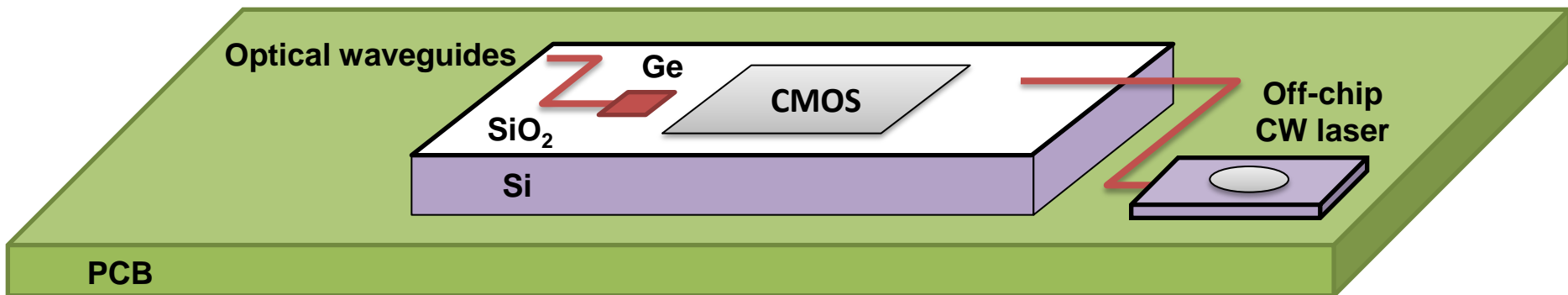
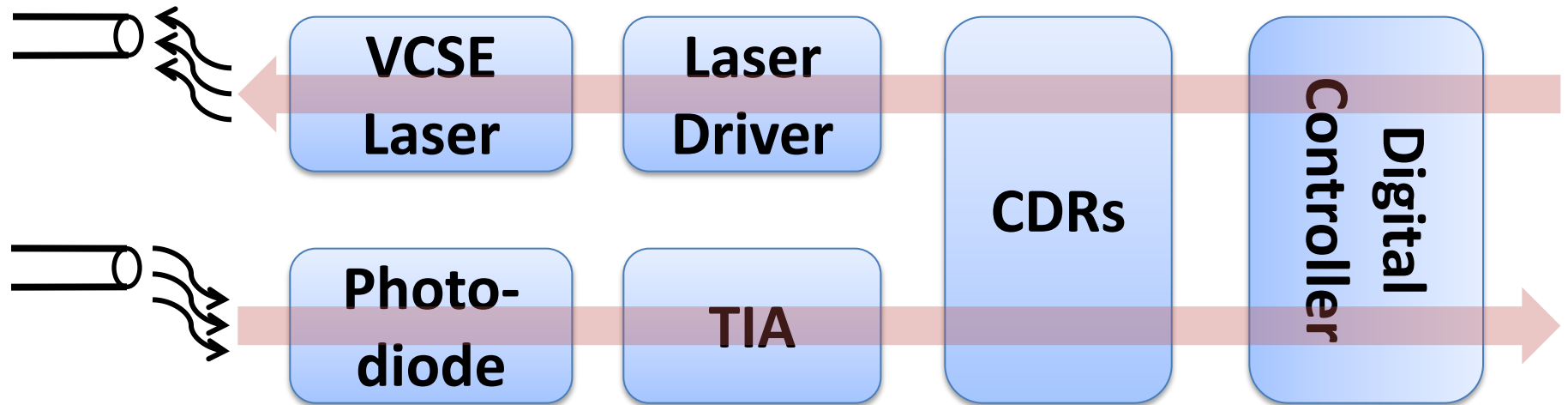


Optical Transceiver – SiP



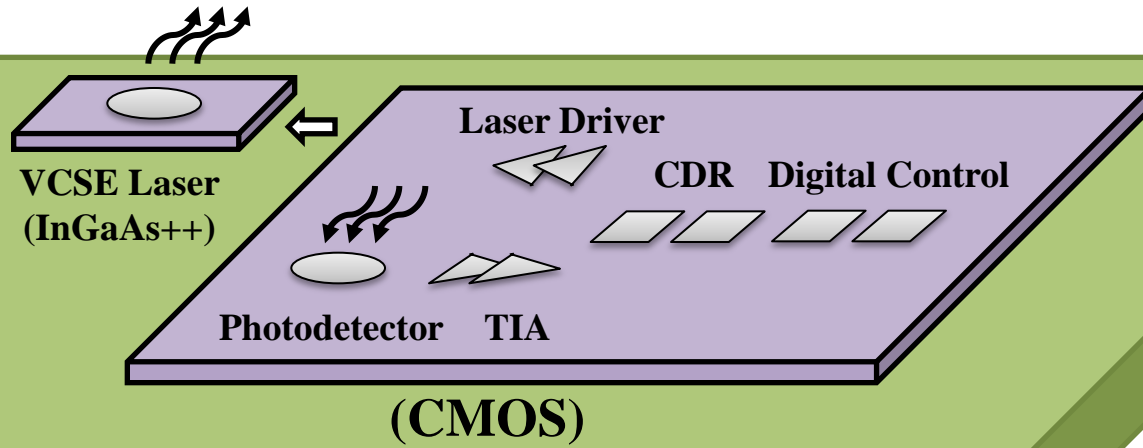
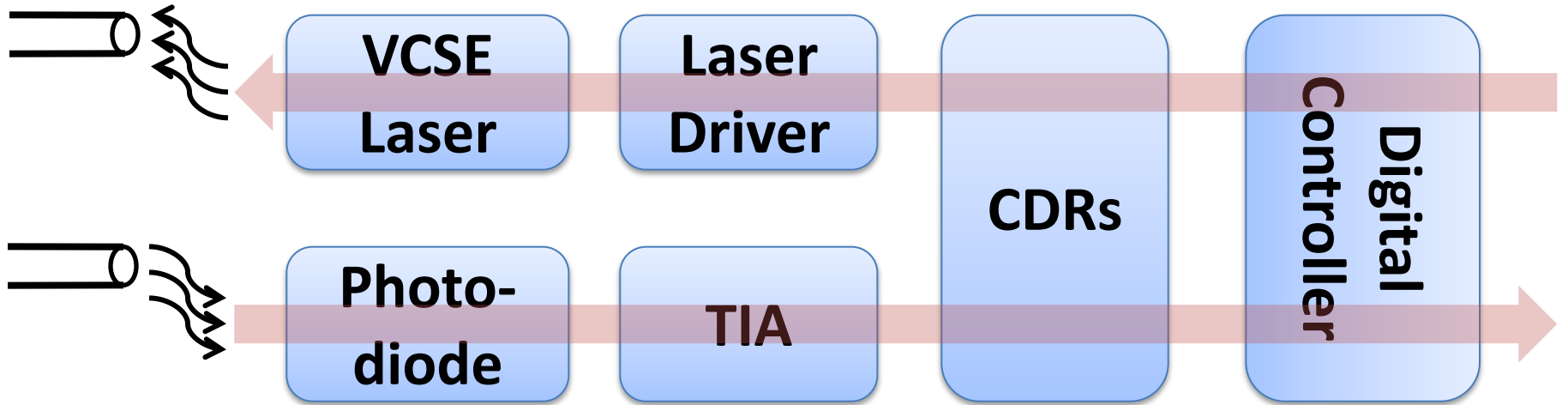
I. Young et al, "Optical I/O technology for tera-scale computing," *JSSC*, Jan. 2010.

Optical Transceiver – Silicon Photonics



e.g. I. Young et al, "Optical I/O technology for tera-scale computing," *JSSC*, Jan. 2010.
Analui et al, "A Fully Integrated 20-Gb/s Optoelectronic Transceiver Implemented in a Standard 0.13- μm CMOS SOI Technology," *JSSC*, Dec. 2006.

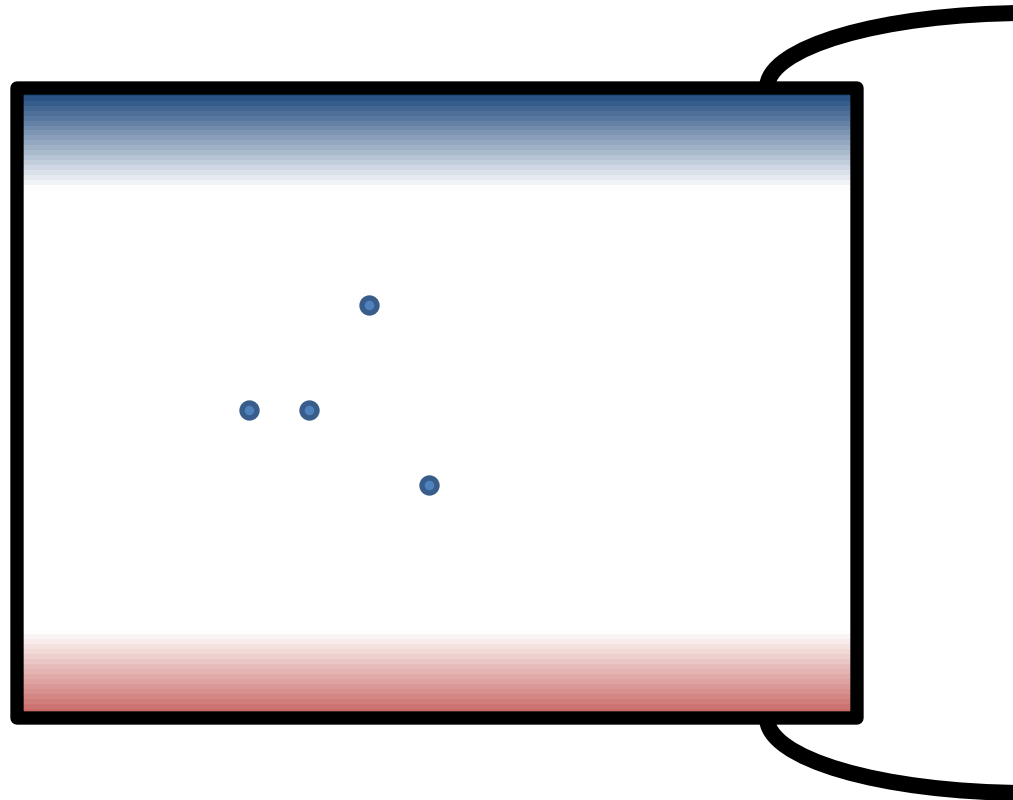
Optical Transceiver



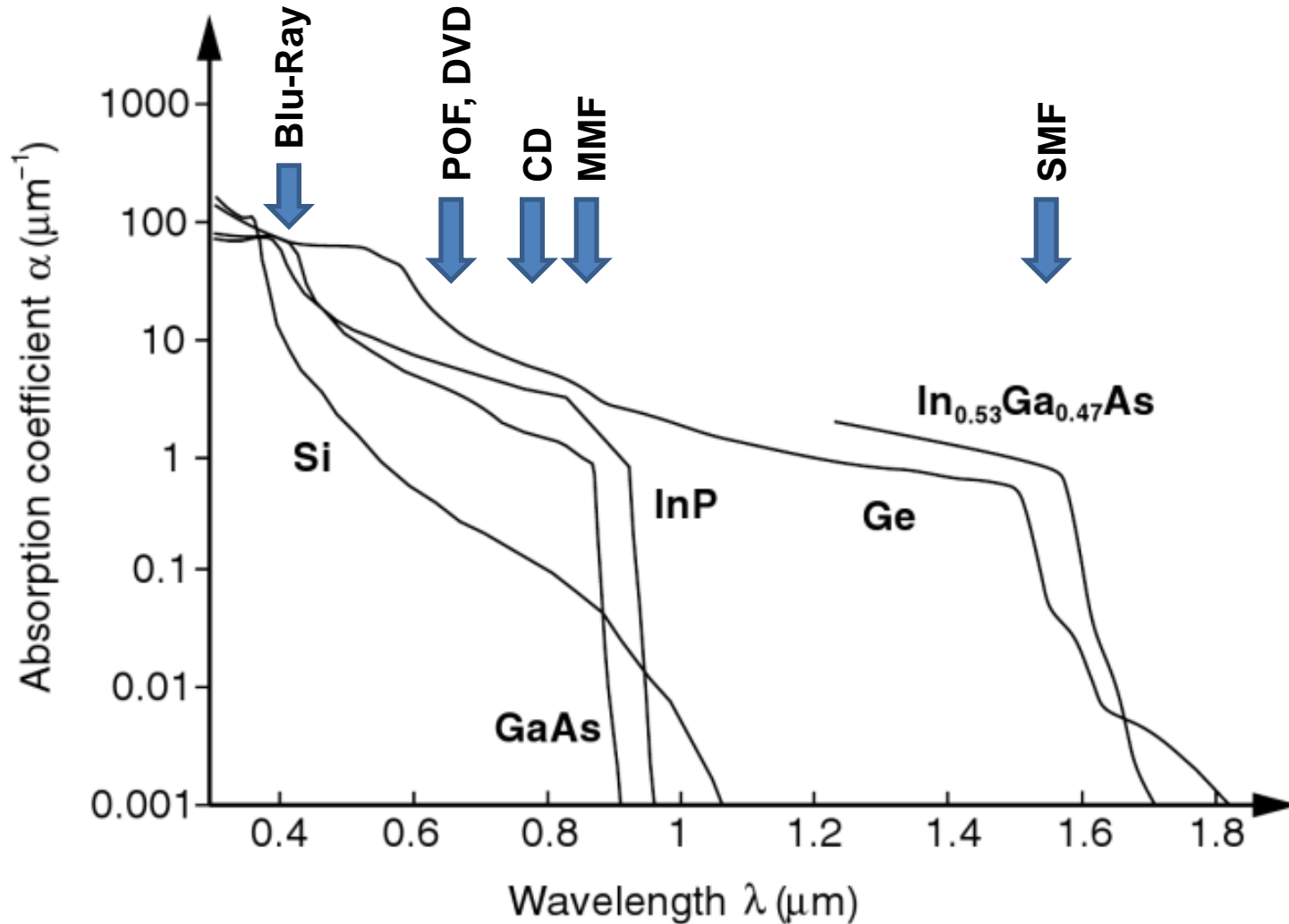
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High-Speed Photodetectors

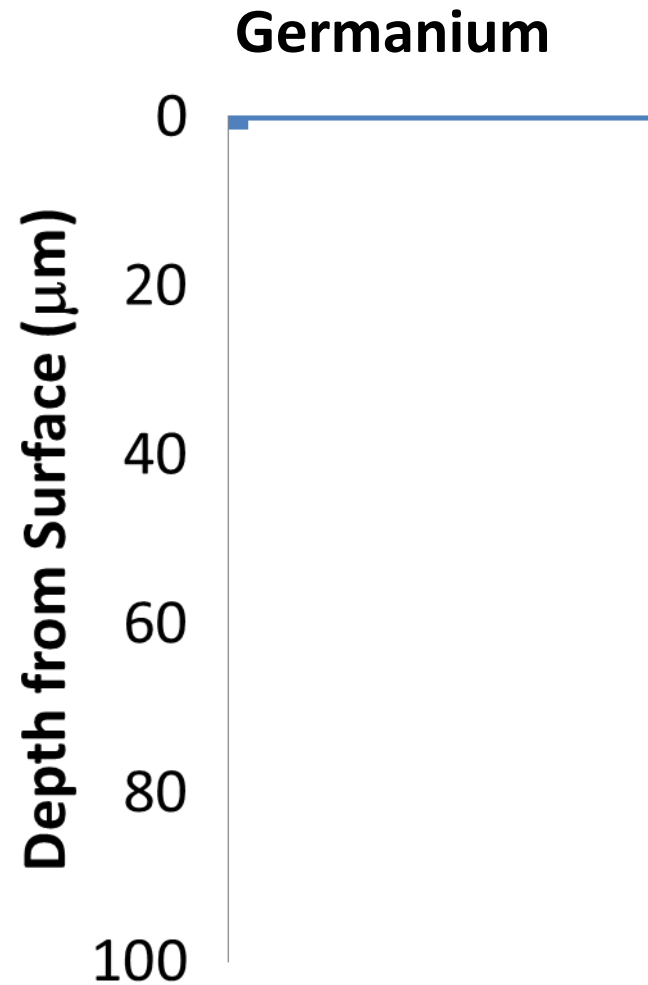
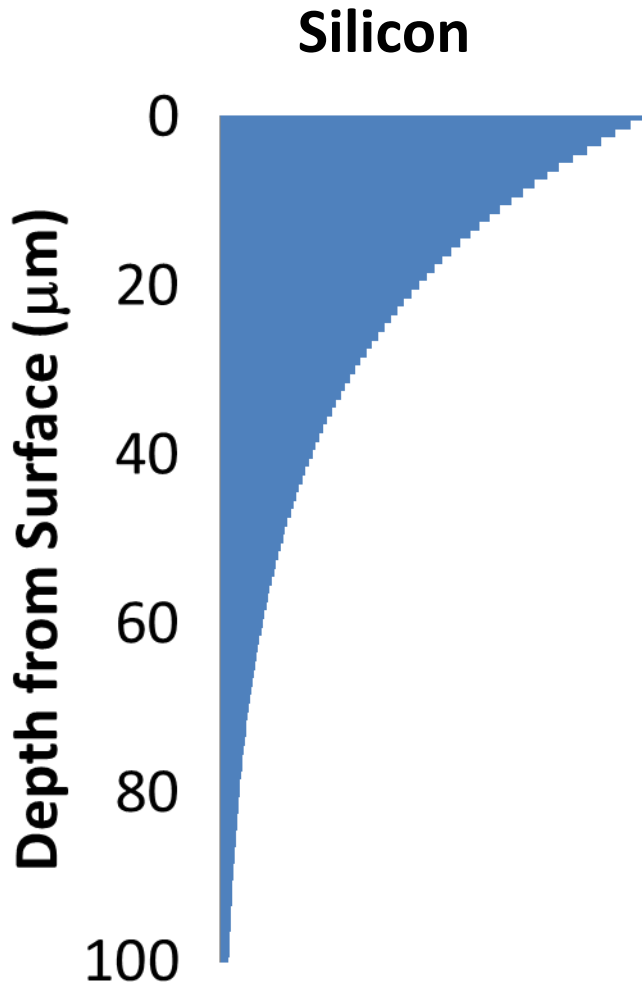


Optical Absorption of Semiconductors



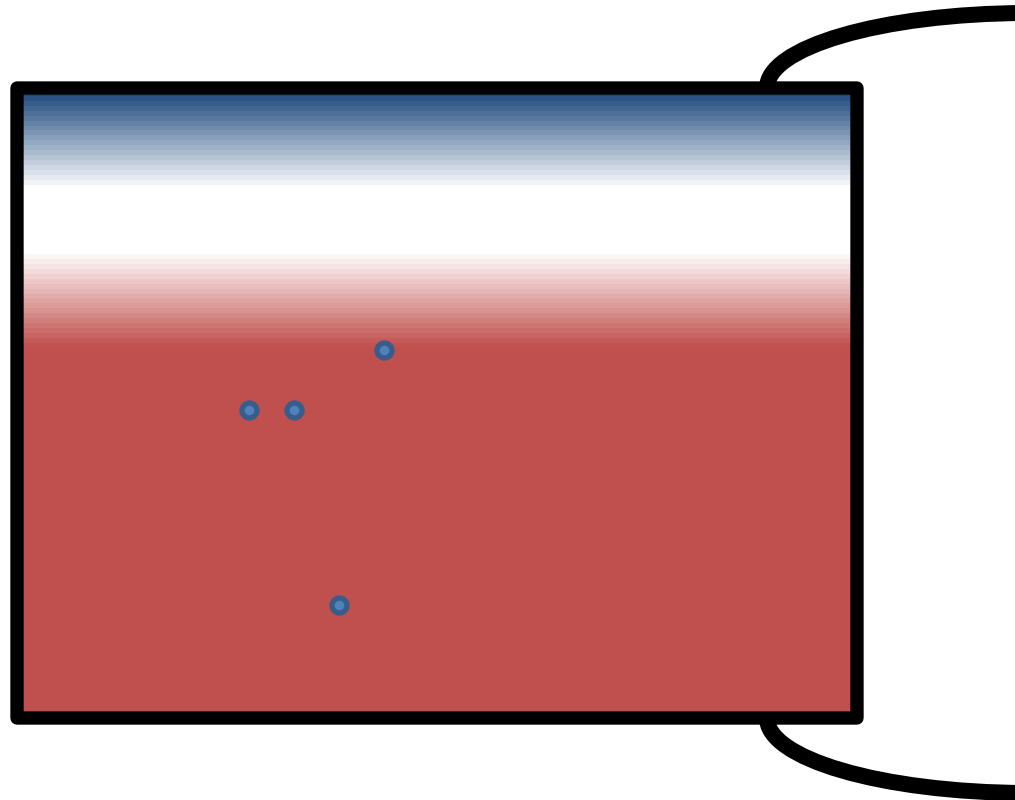
From: H. Zimmermann, *Silicon Optoelectronic Integrated Circuits*, Springer, 2004.

Absorption PDF of light at $\lambda = 850$ nm



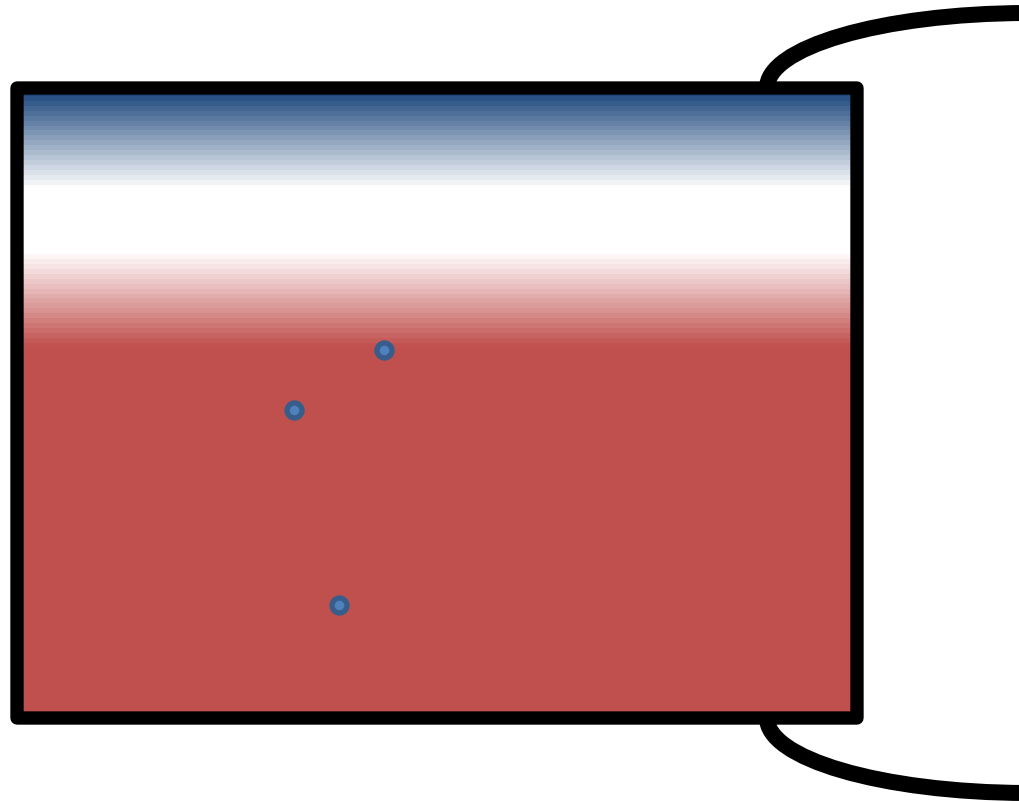
CMOS Photodetectors

...

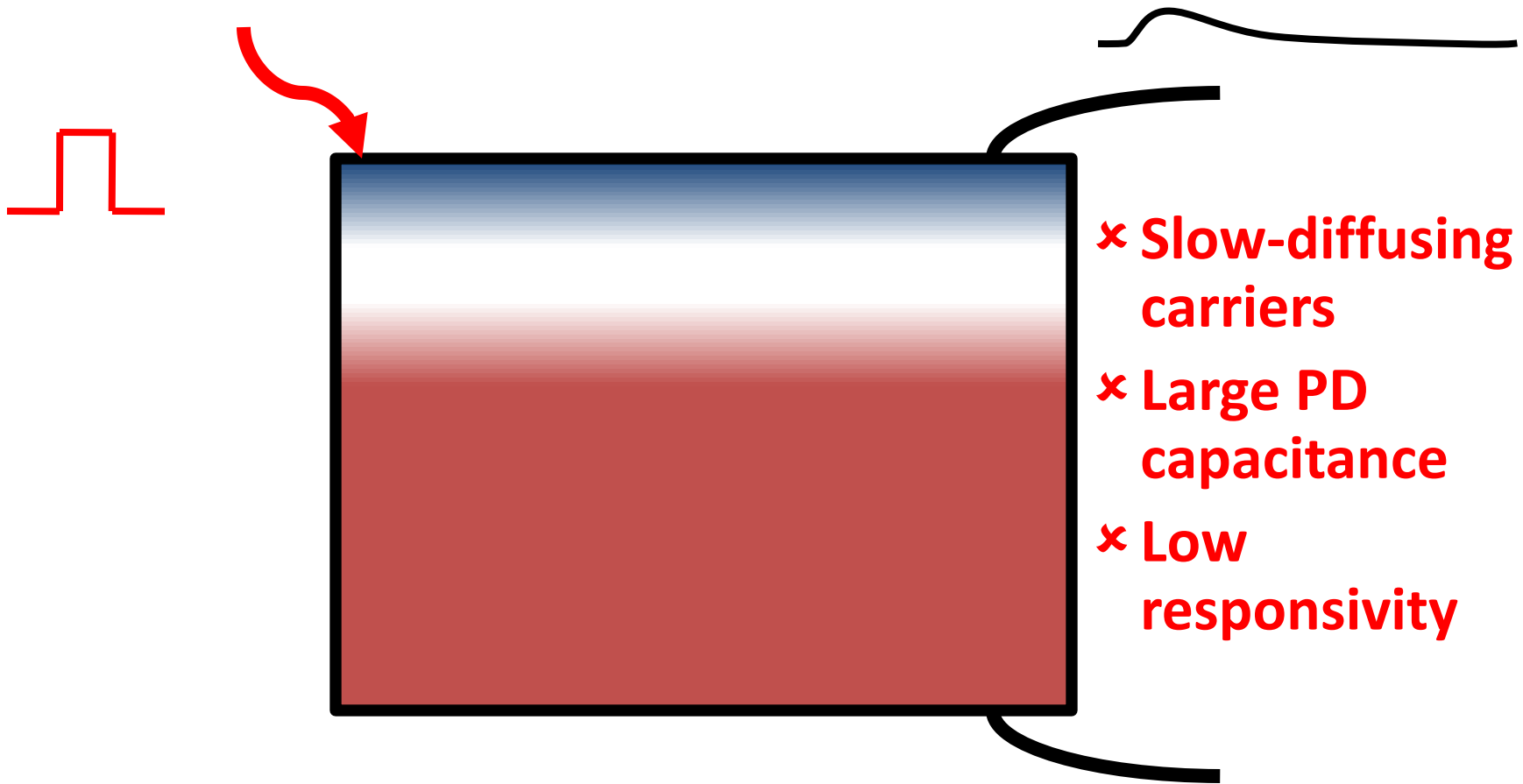


Recombination

...

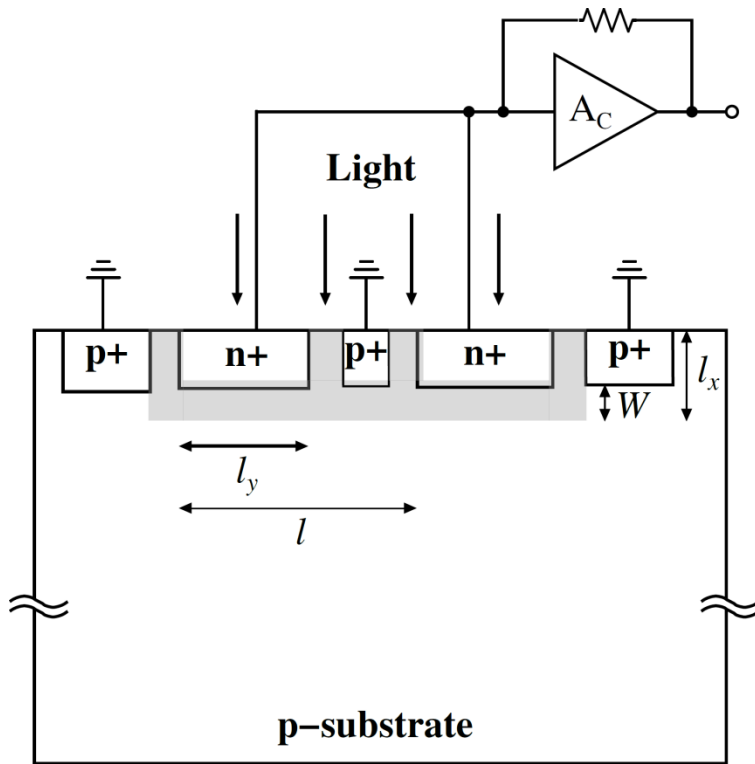


CMOS Photodetectors

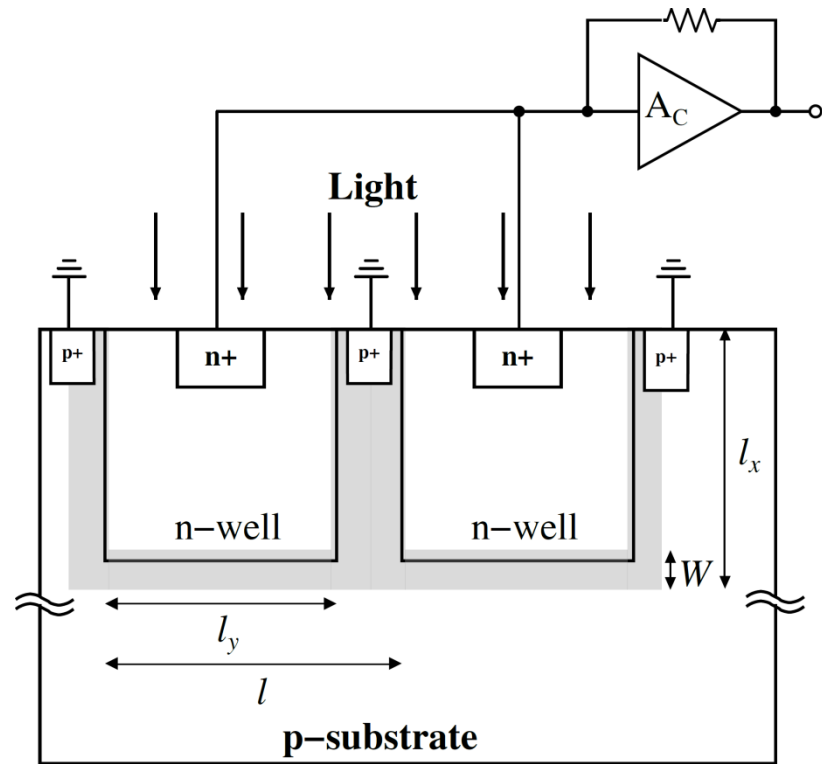


CMOS Photodetector Examples

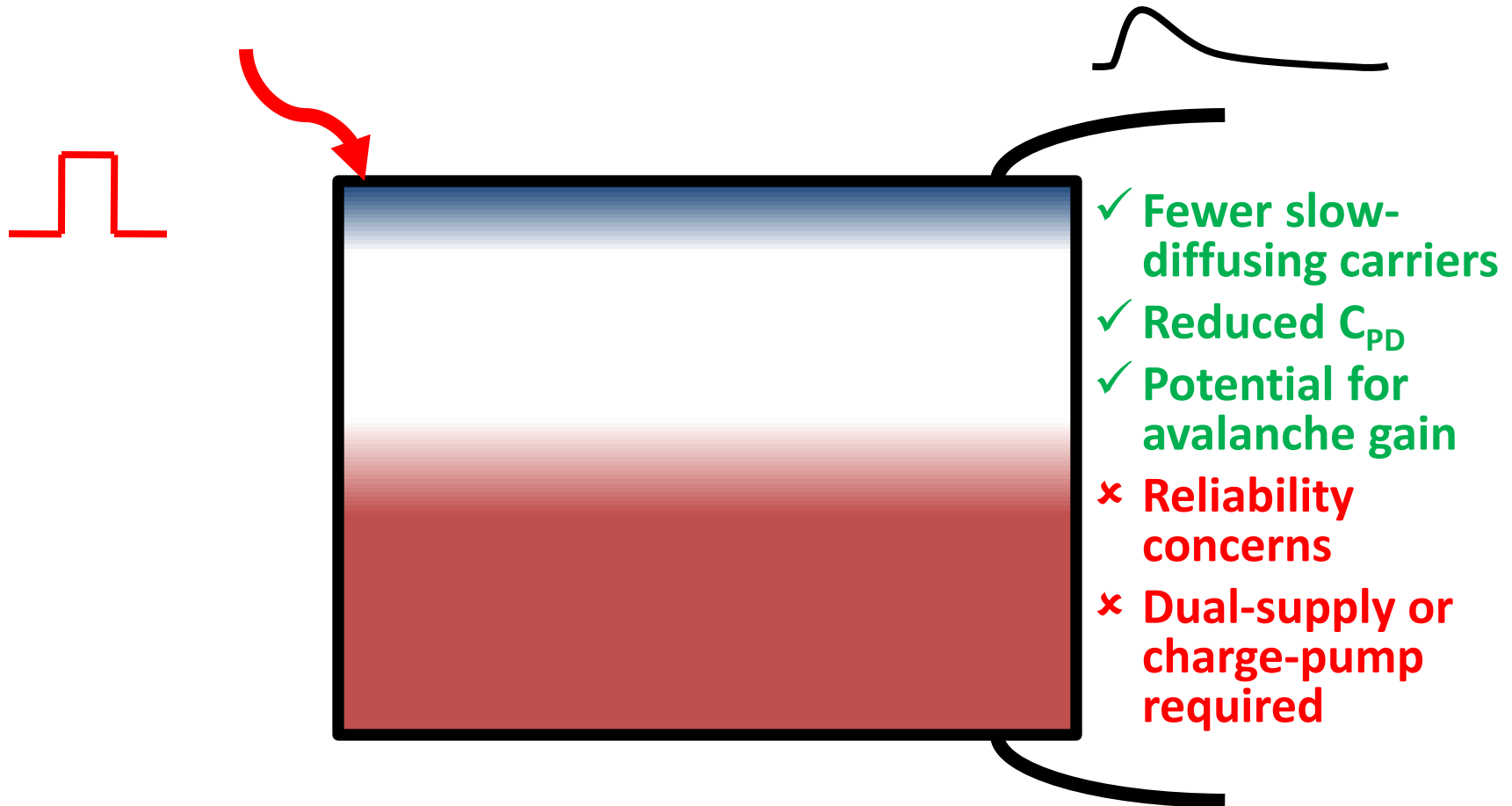
n+/p



n-well/p



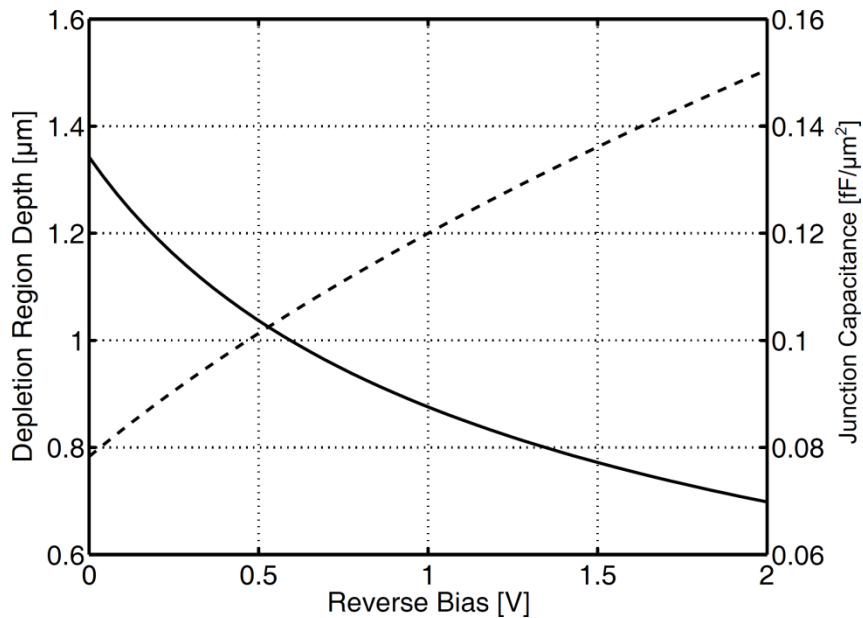
High Reverse Bias



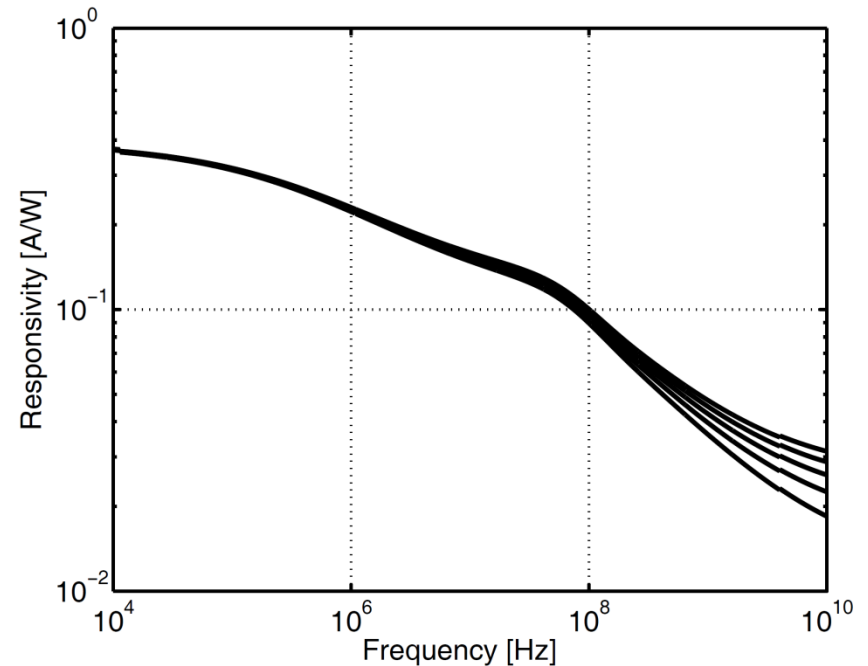
e.g. 14.2-V reverse bias in S.-H. Huang & W.-Z. Chen, "A 10-Gbps CMOS single chip optical receiver with 2-D meshed spatially-modulated light detector," *CICC*, Sept. 2009

Impact of Reverse Bias Voltage

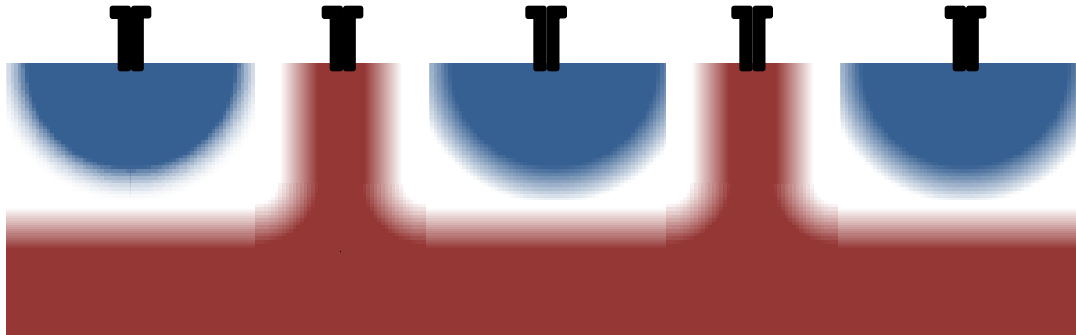
Junction capacitance



Intrinsic frequency response



Layout Considerations



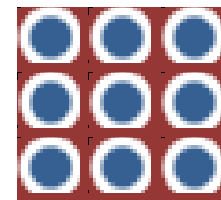
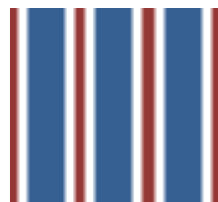
Few/Wider strips:

- ✓ Less contact metal blocking light
- ✓ Smaller C_{PD}

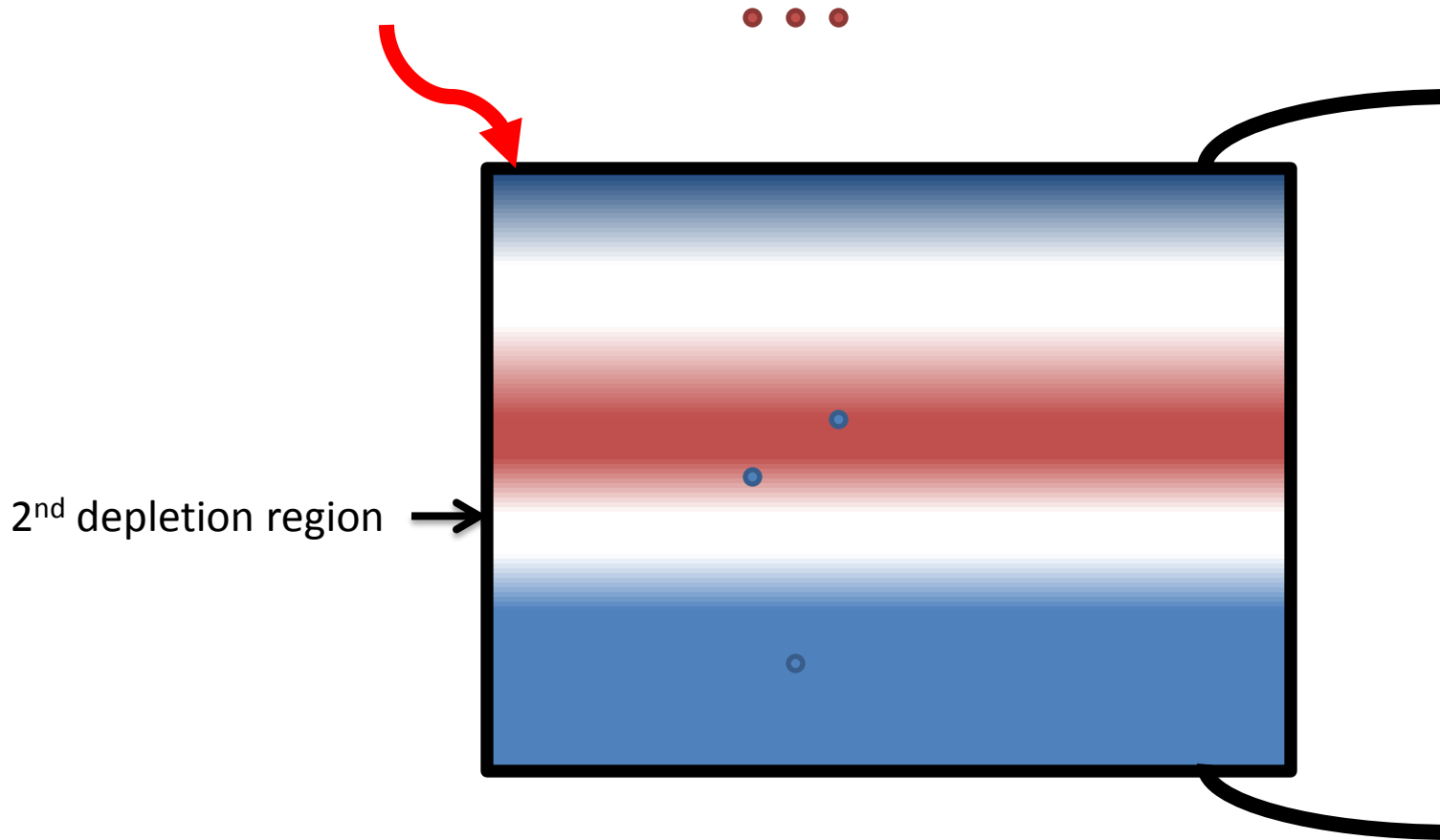
More/Smaller strips:

- ✓ Short diffusion times for the carriers to get to the contacts
- ✓ Additional sidewall depletion regions for light absorption

Similar tradeoffs arise between 1-D and 2-D contact arrays

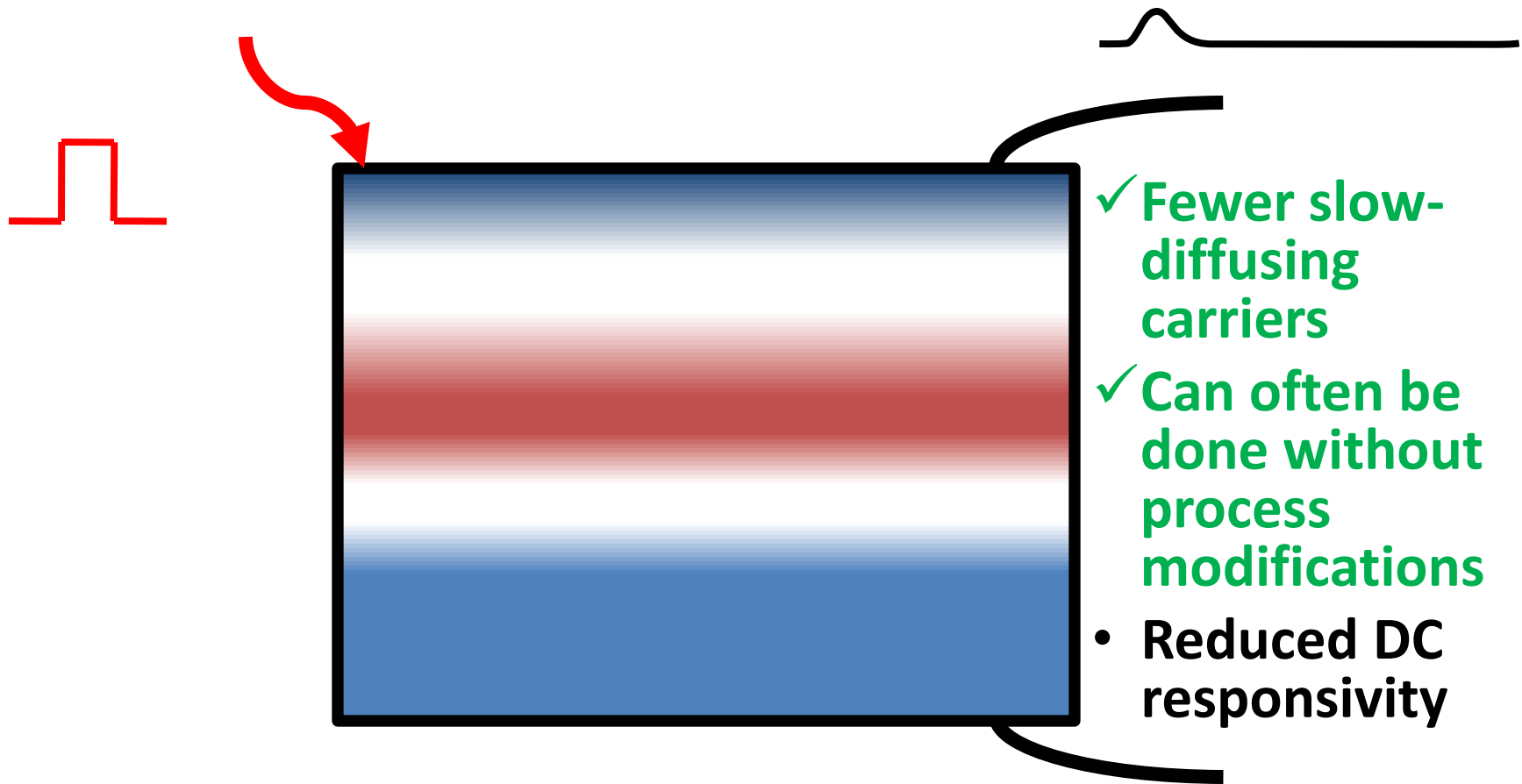


Diffusion-Shielded Photodetectors



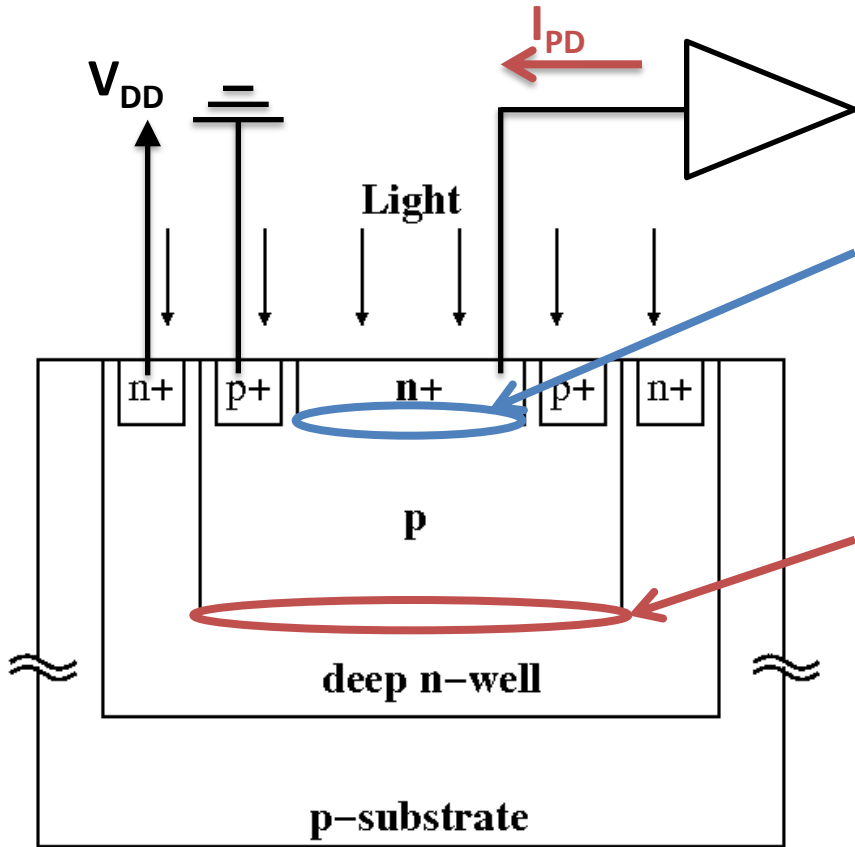
Similar effect provided by SOI

Diffusion-Shielded Photodetectors



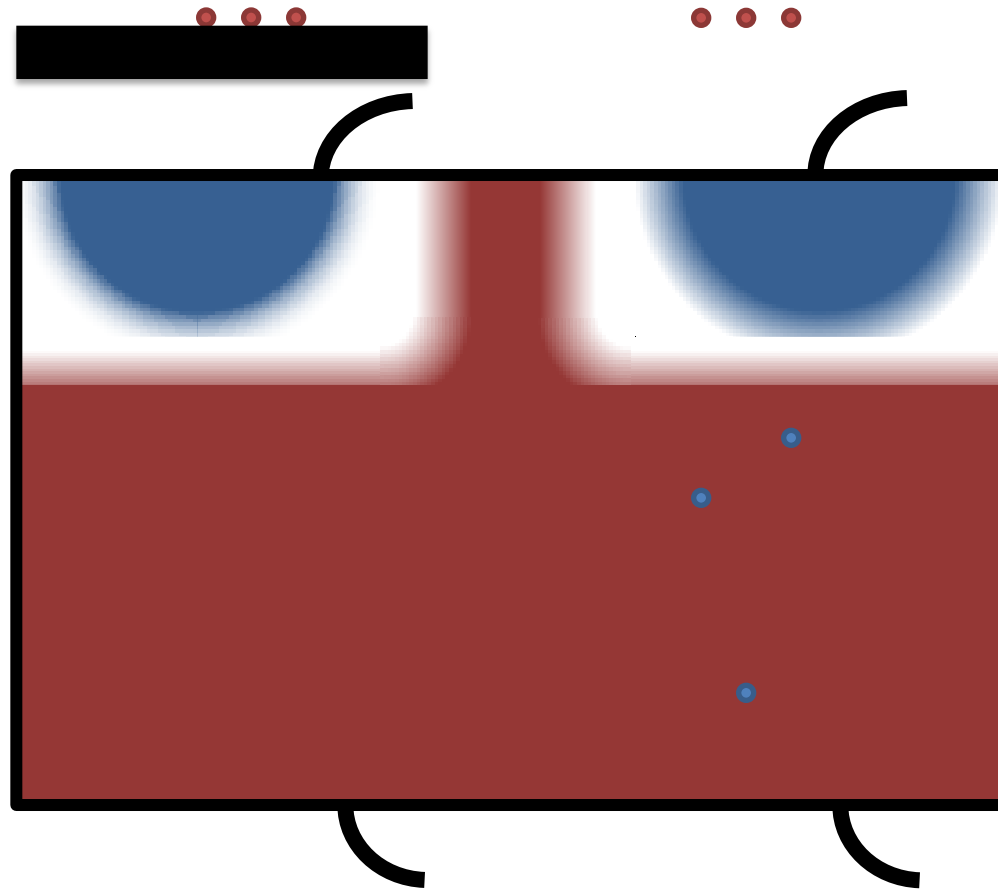
P. J. Lim et al, "A 3.3-V monolithic photodetector/CMOS preamplifier for 531 Mb/s optical data link applications," *ISSCC 1993*
T.K. Woodward & A.V. Krishnamoorthy, "1 Gbit/s CMOS photoreceiver with integrated detector operating at 850 nm,"
Electronics Letters, Jun 1998.

Diffusion-Shielded Photodetector Example

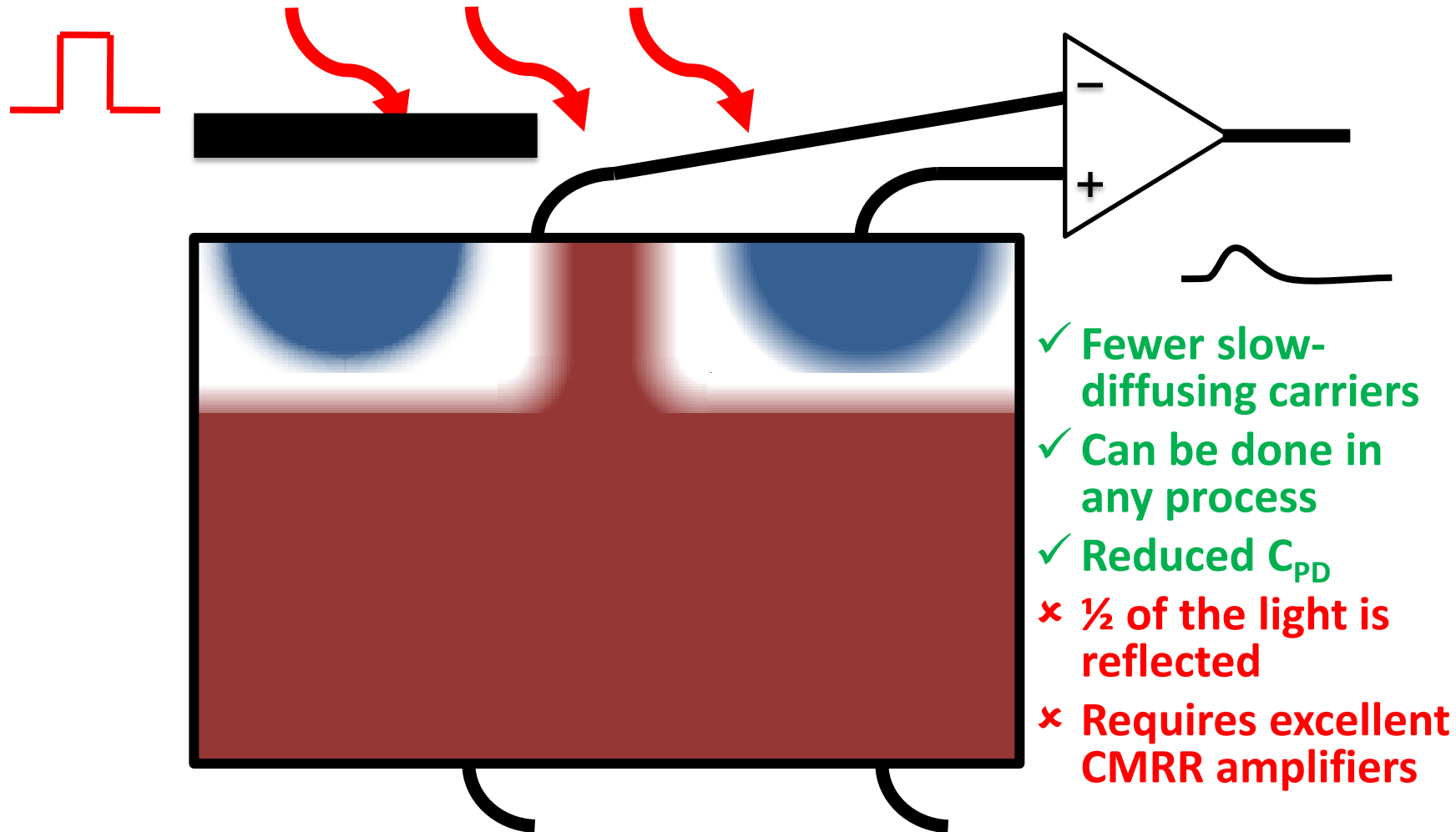


- n+/p junction is reverse-biased and used as the active photodetector
- p/n-well junction is reverse biased to collect and discard photocarriers generated far below the n+/p junction

Spatially Modulated Photodetectors

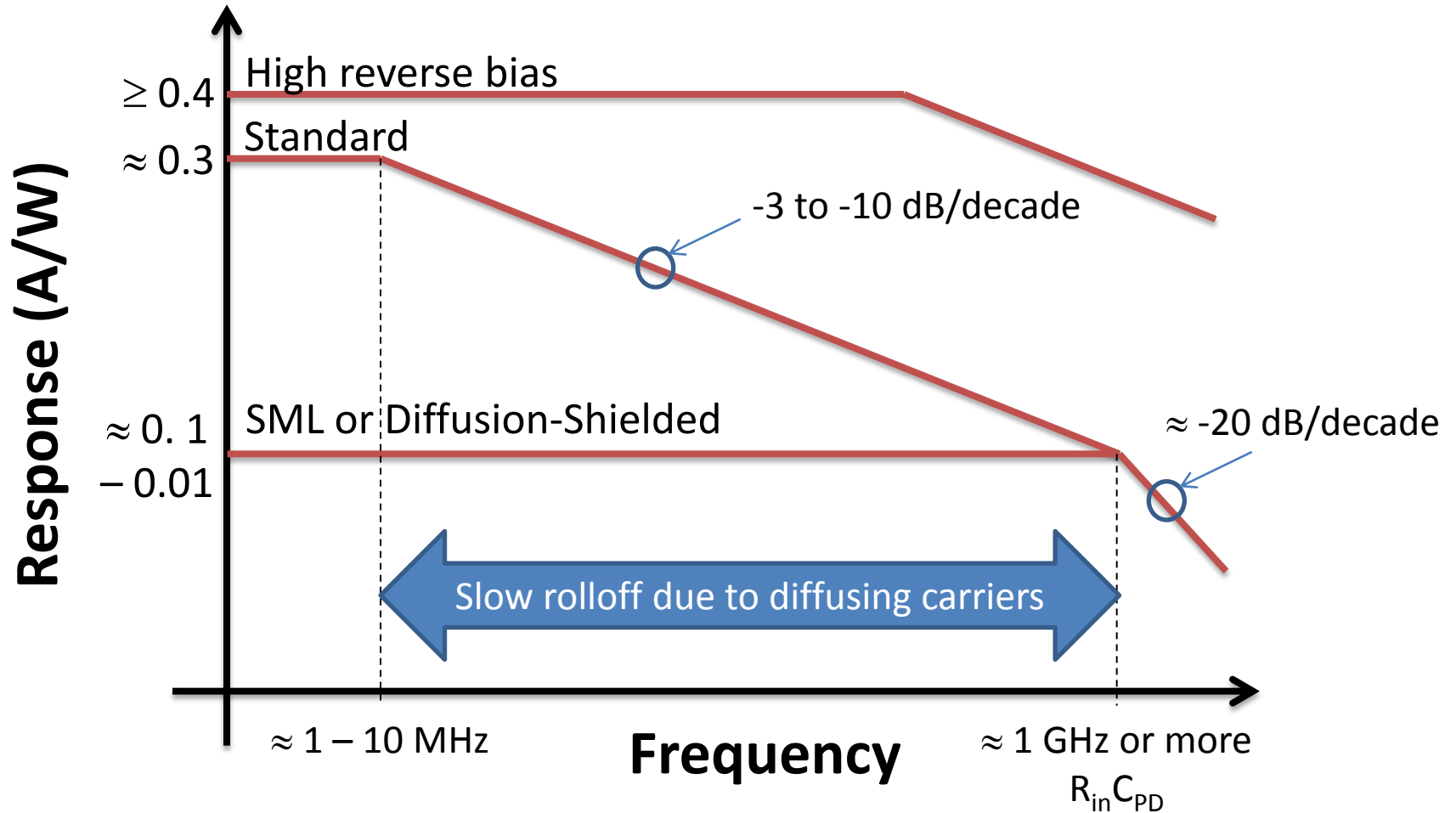


Spatially Modulated Photodetectors



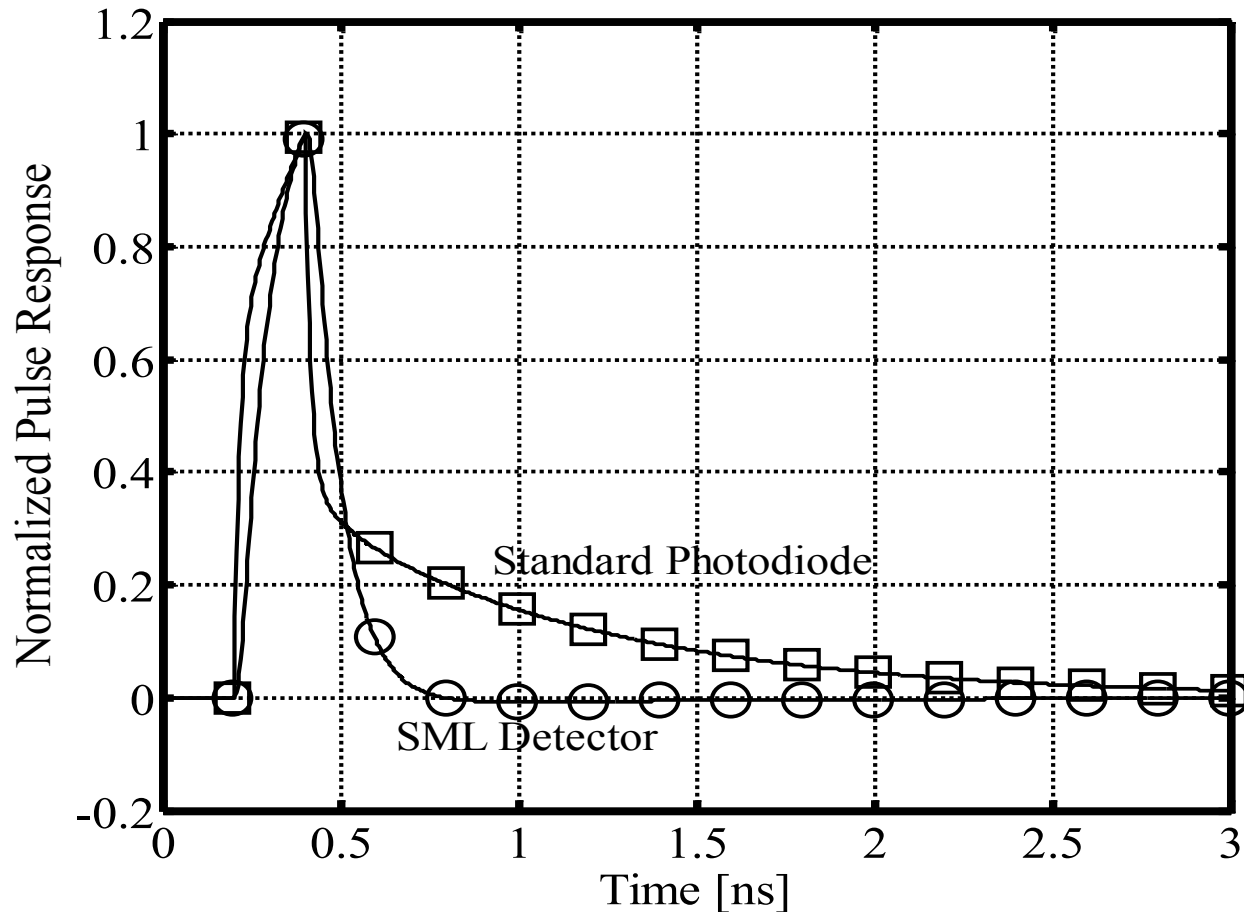
Kuijk et al, "Spatially modulated light detector in CMOS with sense-amplifier receiver operating at 180 Mb/s for optical data link applications and parallel optical interconnects between chips," *IEEE J. Sel. Top. Quant. Elec.*, Nov/Dec 1998.

Typical CMOS PD Frequency Responses



Representative of photodiodes in 0.18 μm CMOS process
with light at $\lambda = 850$ nm

Typical CMOS PD Pulse Responses

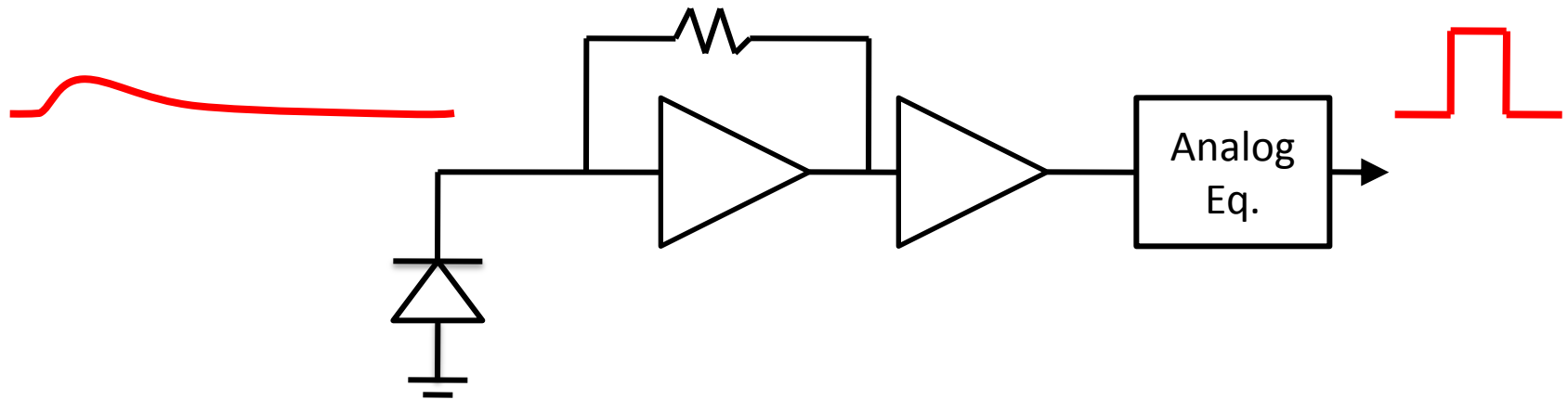


Representative of photodiodes in 0.18 μm CMOS process
with light at $\lambda = 850 \text{ nm}$ at 5 Gbps

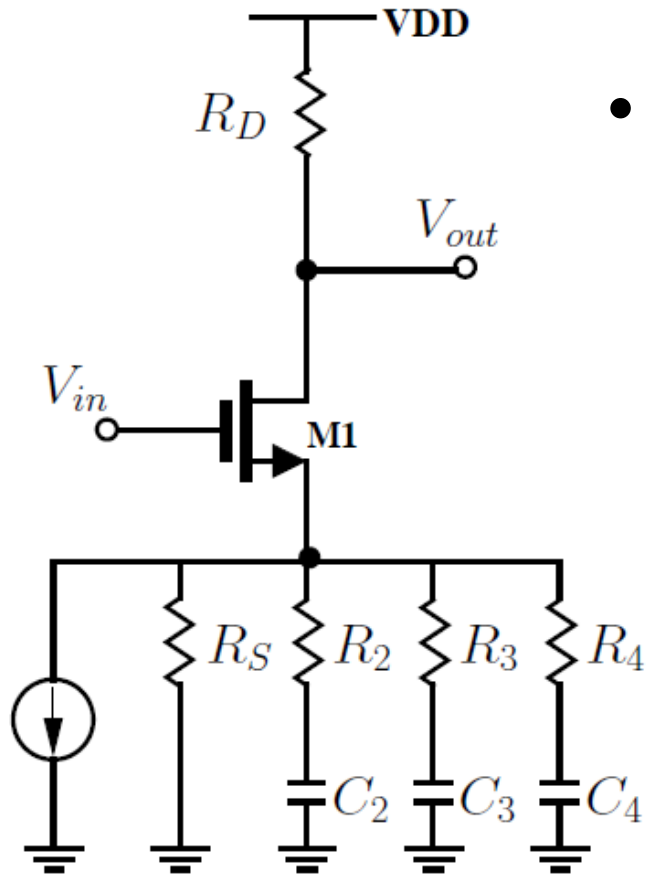
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Equalization of the Pulse Response



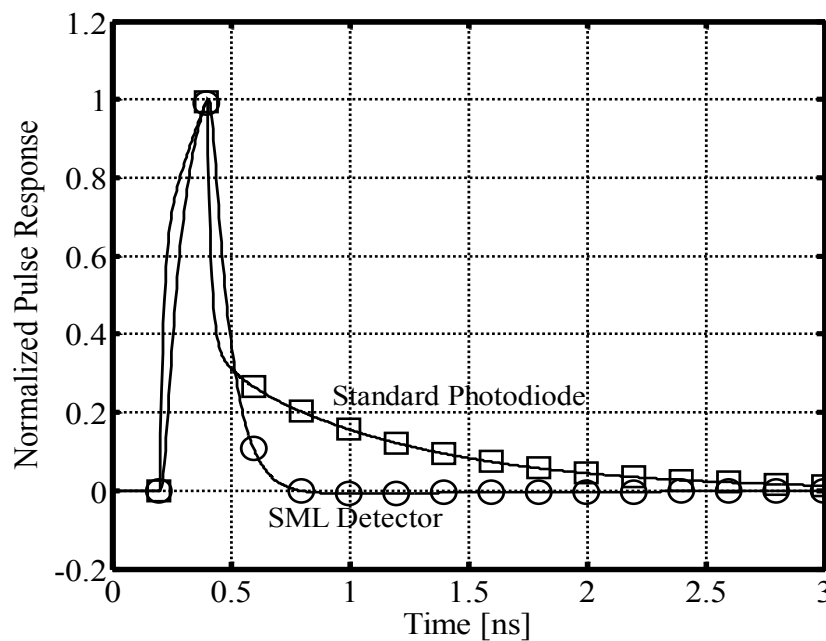
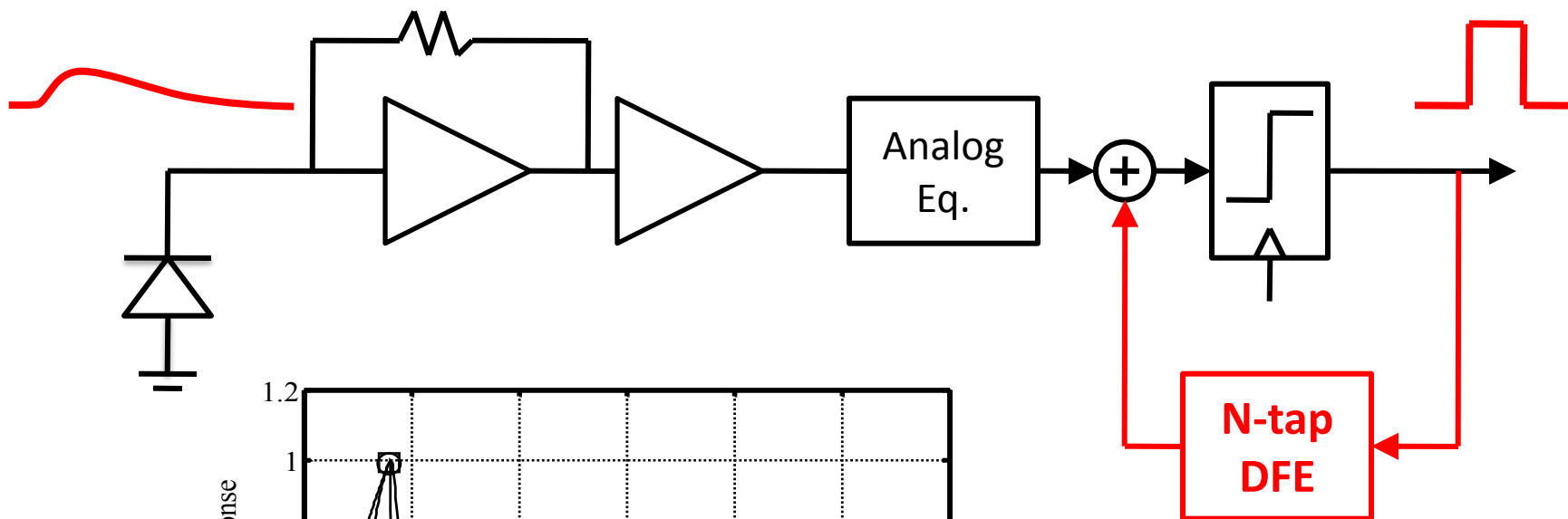
Analog Equalization



- High-order transfer function is required to equalize the ≈ 5 dB/decade slope

Radovanovic, Annema, Nauta, "A 3-Gb/s optical detector in standard CMOS for 850-nm optical communication," *JSSC*, Aug. 2005.

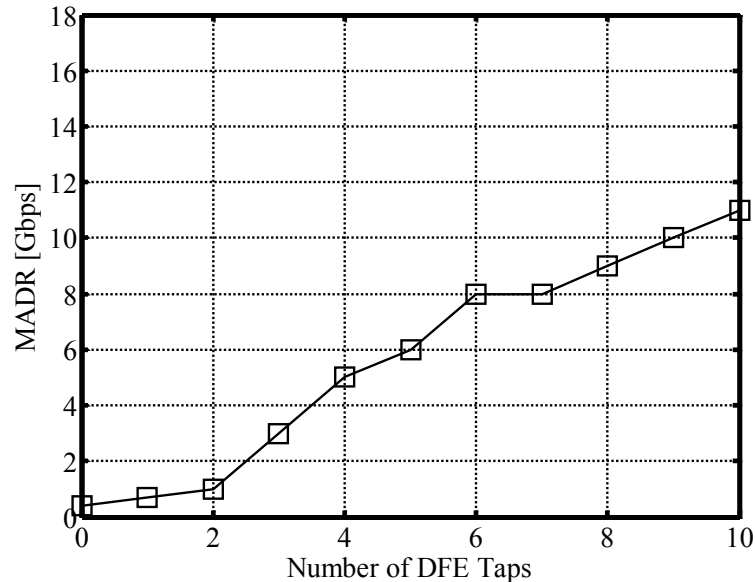
Equalization of the Pulse Response



Mostly post-cursor pulse responses suggest that a DFE may be effective

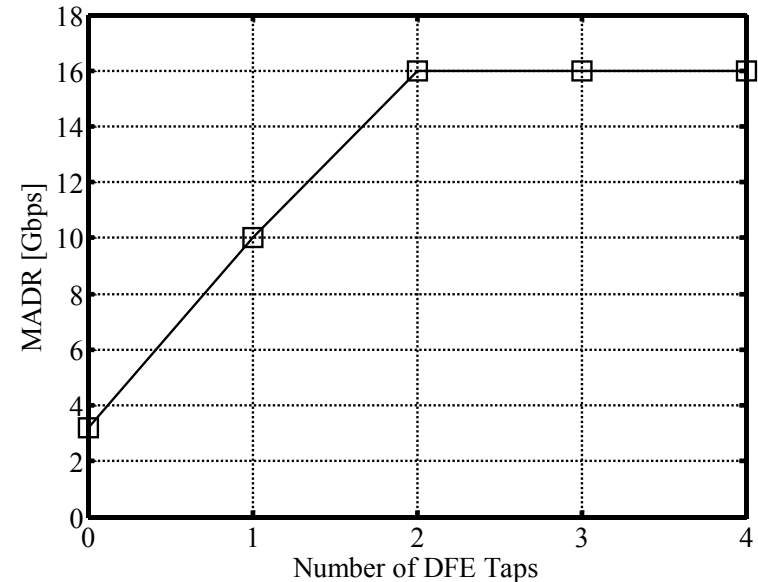
Maximum Data Rates: Analog Eq. + DFE

Standard Photodetector



- Many DFE taps are required to accurately cancel the distant post-cursor ISI

SML Photodetector



- High-gain low-noise TIA is required due to the reduced responsivity of an SML detector

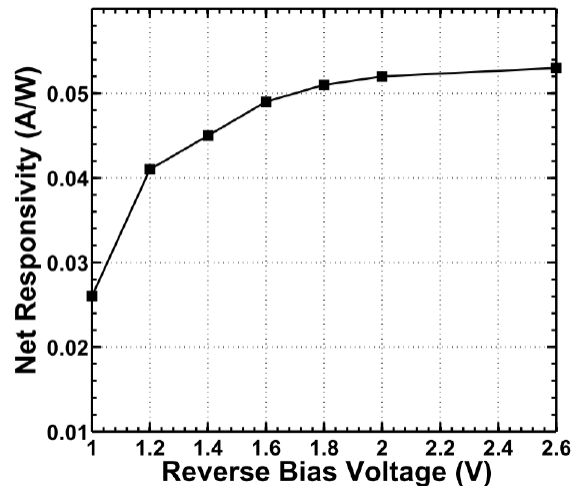
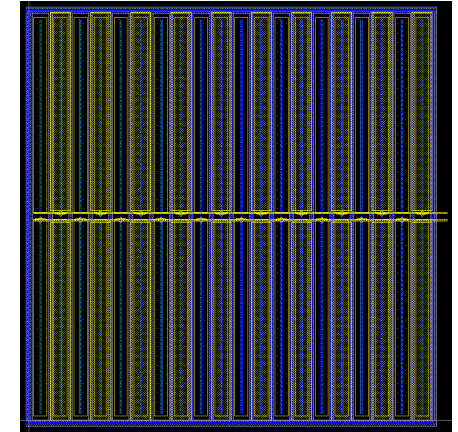
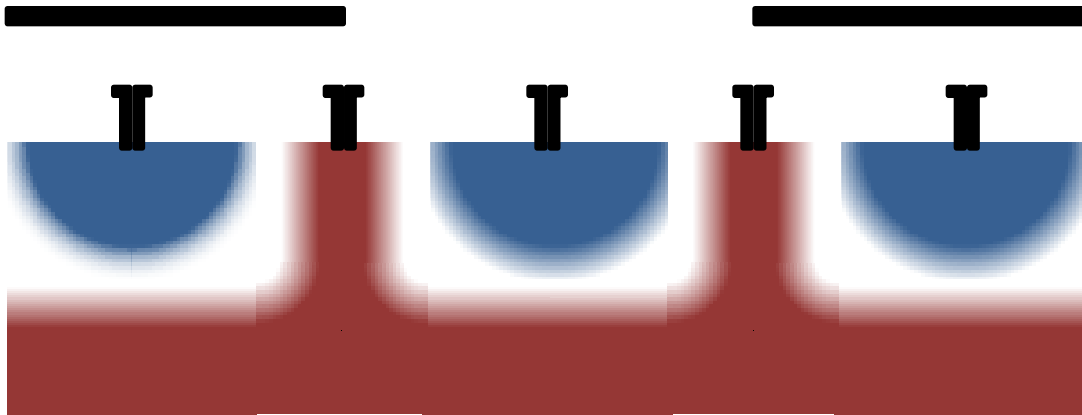
High-Speed CMOS Photodetector Summary

- Slowly-diffusing carriers
 - Maximize depletion regions via layout
 - ⇒ increases capacitance
 - Maximize depletion regions via large reverse bias
 - ⇒ need for dual-supplies or charge pump, reliability concerns
 - Shield diffusing carriers
 - Signal processing techniques:
 - SML ⇒ decreases responsivity
 - equalization
- Low responsivity
 - Low-noise/high-sensitivity TIA
- High capacitance
 - Low input-resistance TIA

Outline

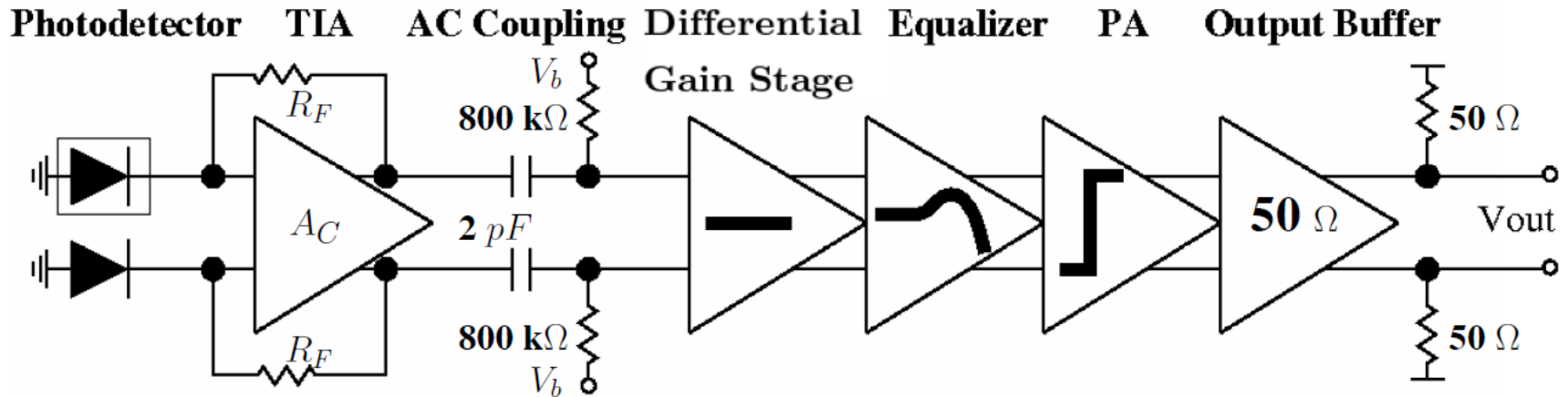
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SML Photodetector Example



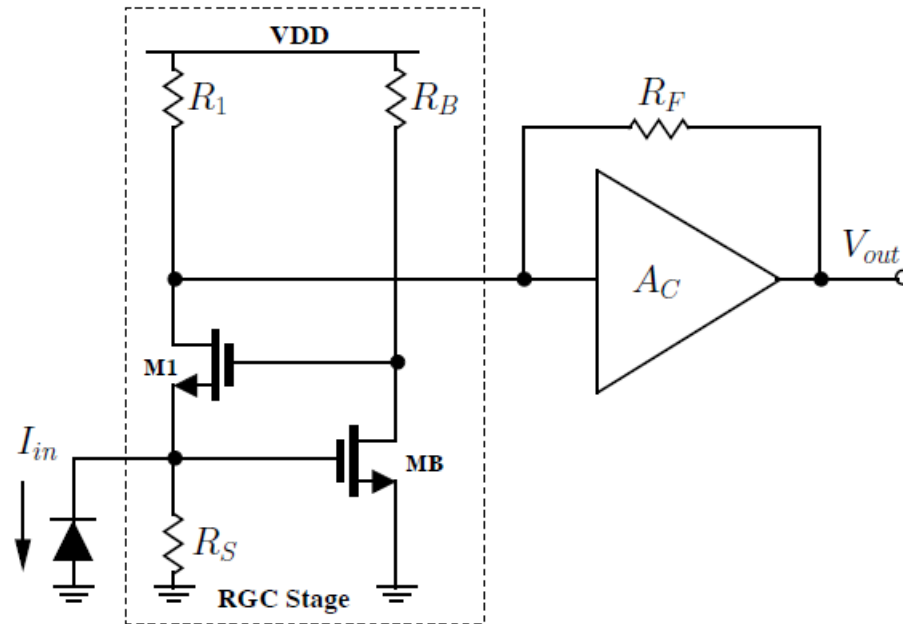
- 0.18 μm bulk CMOS process
- M1 is used for contacts, M2 is used to block light
- Junction side-walls also collect photons
- 20 strips (10 light + 10 dark) across a 75 μm x 75 μm area

System Design



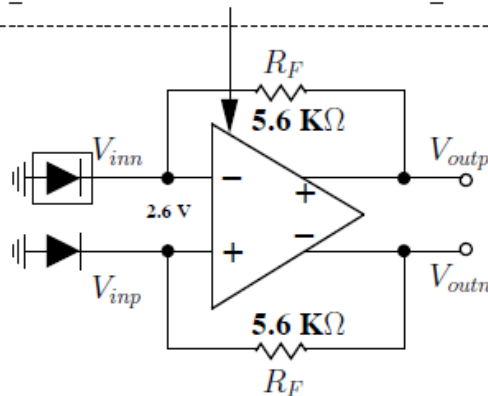
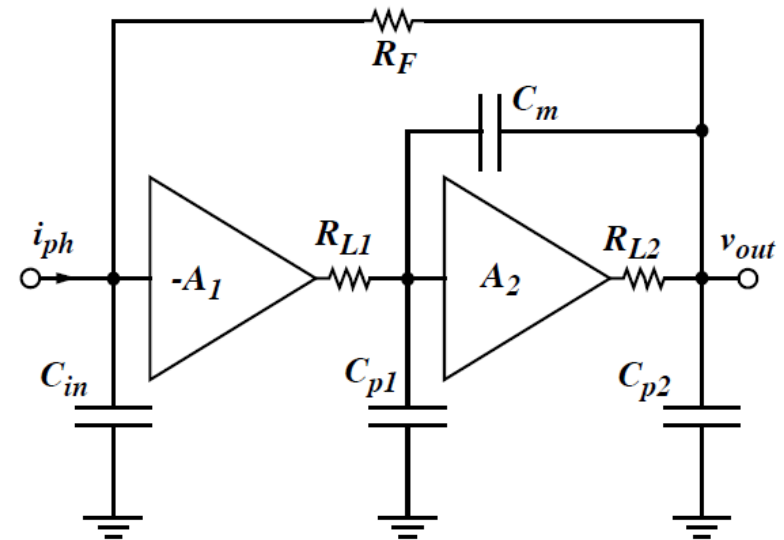
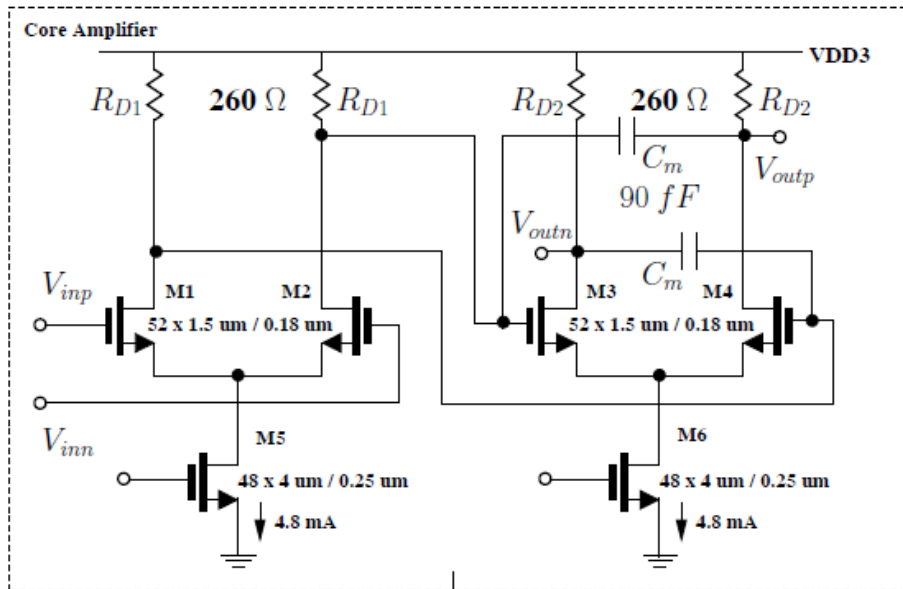
- Responsivity, $R = 0.03\text{ A/W}$ & Input optical power of $-5\text{ dBm} \Rightarrow$ **Photodiode current, $I_{PD} = 9\ \mu\text{A}$**
- $\text{BER} = 10^{-12} \Rightarrow$ **TIA input-referred noise of $0.65\ \mu\text{A}_{\text{rms}}$**
- TIA output of 50 mV makes noise performance of subsequent stages non-critical \Rightarrow **$R_F = 5.6\text{ k}\Omega$**
- Similar architecture reported in:
 - C. Hermans et al, "A Gigabit optical receiver with monolithically integrated photodiode in $0.18\text{-}\mu\text{m}$ CMOS," *ESSCIRC*, Sept. 2006.
 - Chen et al, "A 3.125 Gbps CMOS Fully Integrated Optical Receiver with Adaptive Analog Equalizer," *ASSCC*, Nov. 2007.
 - Tavernier & Steyaert, "High-Speed Optical Receivers With Integrated Photodiode in 130 nm CMOS," *JSSC*, Oct. 2009.
 - Lee et al, "An 8.5 Gb/s CMOS OEIC with on-chip photodiode for short-distance optical communications," *ISSCC*, Feb. 2010.

Regulated Cascode Input?



- Low responsivity SML detector
- High system bandwidth (5-Gbps)
- Very low input-referred noise required
- **No regulated cascode at the input**

Transimpedance Amplifier



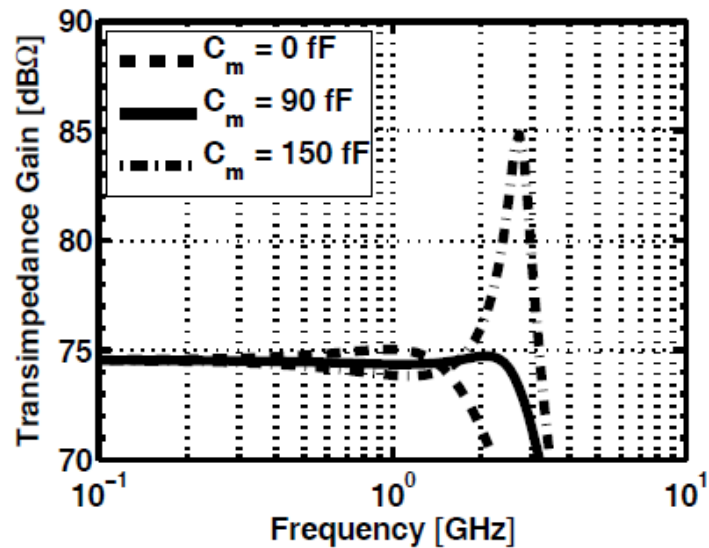
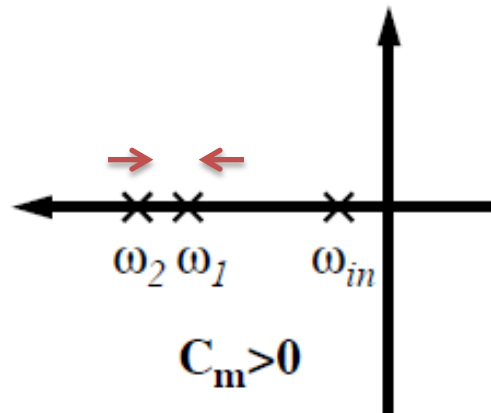
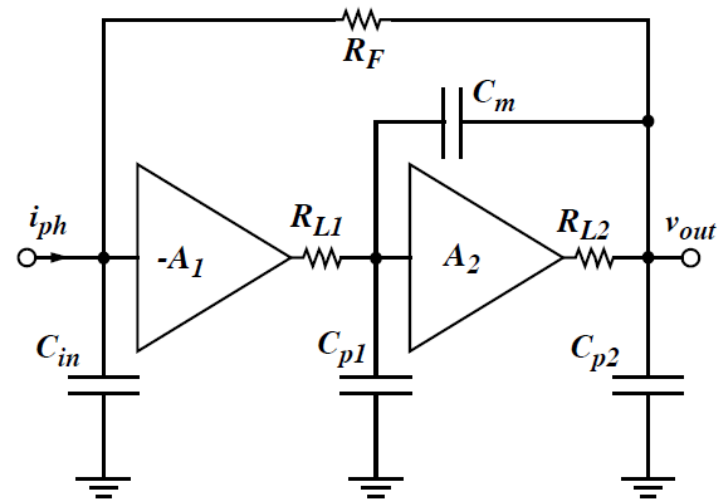
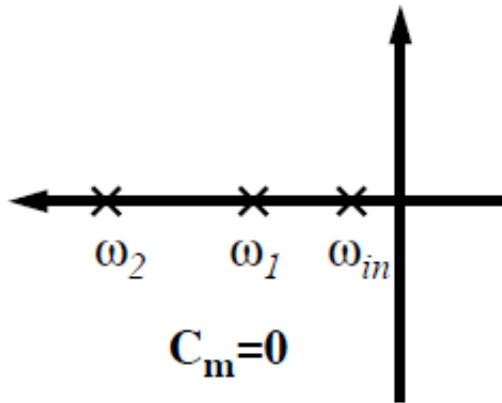
$$C_{in} = C_{PD} + C_{A1} \\ \approx 500 \text{ fF} + 500 \text{ fF} = 1 \text{ pF}$$

$$C_{p1} \approx 680 \text{ fF}$$

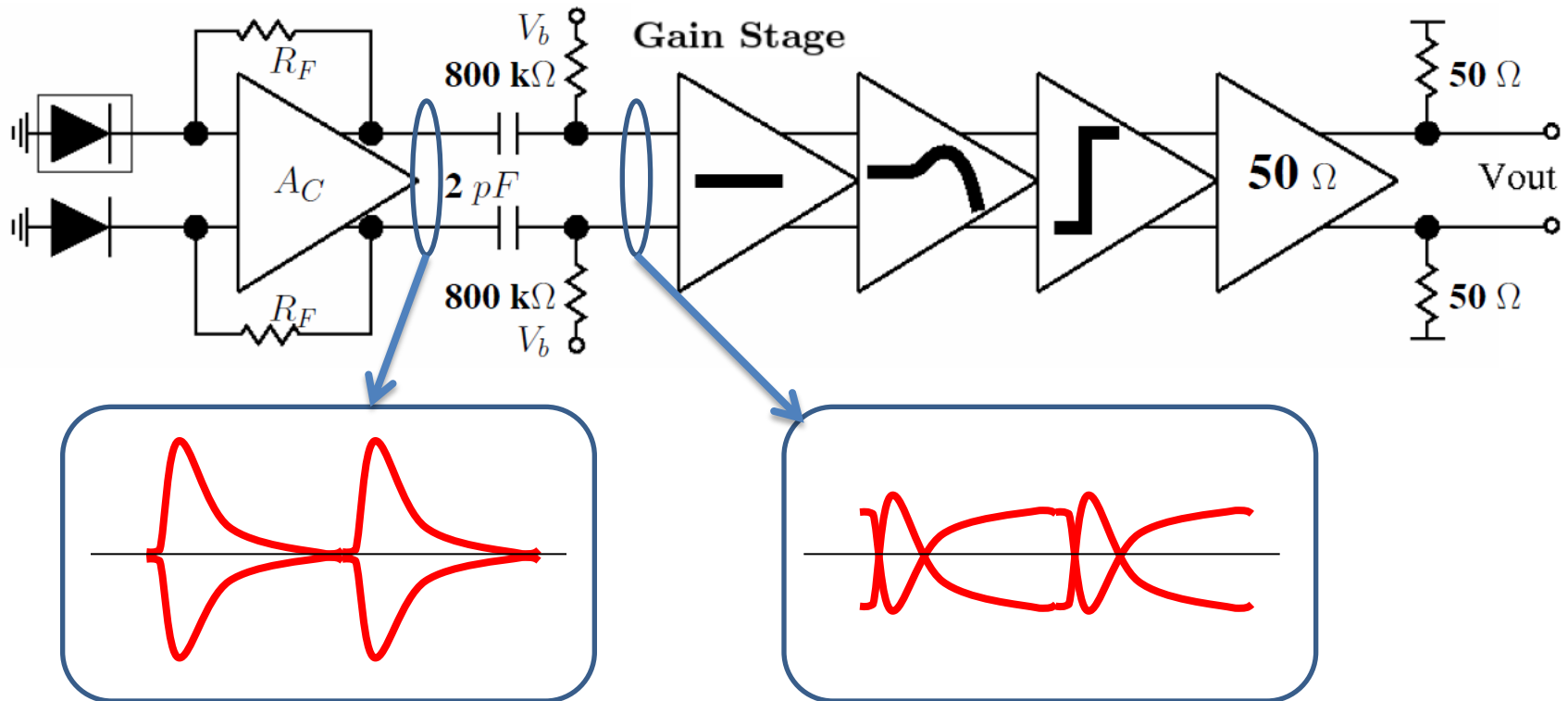
$$C_{p2} \approx 100 \text{ fF}$$

Notice $V_{PD,dc} \approx V_{DD} - 625 \text{ mV}$

Transimpedance Amplifier

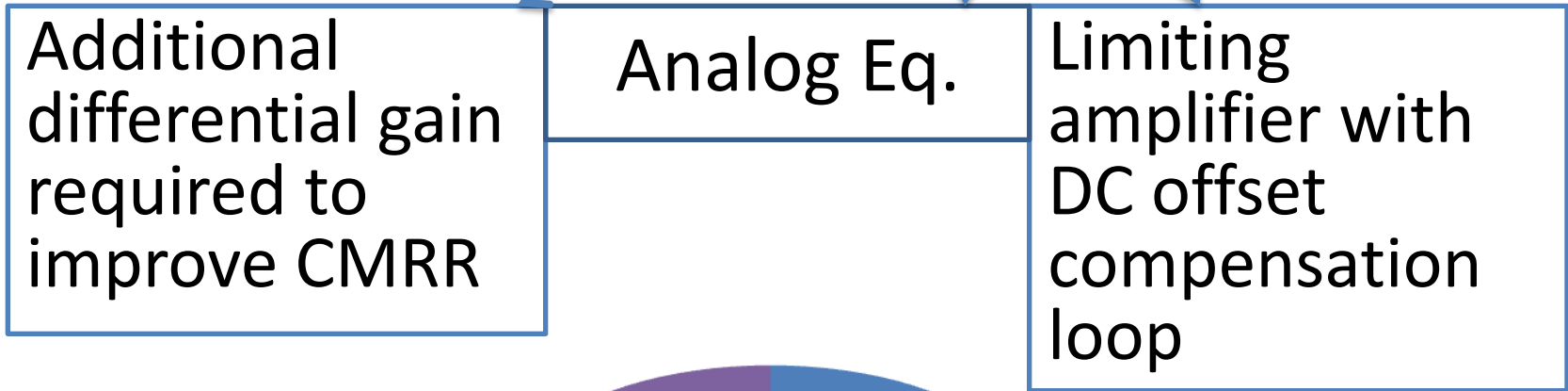
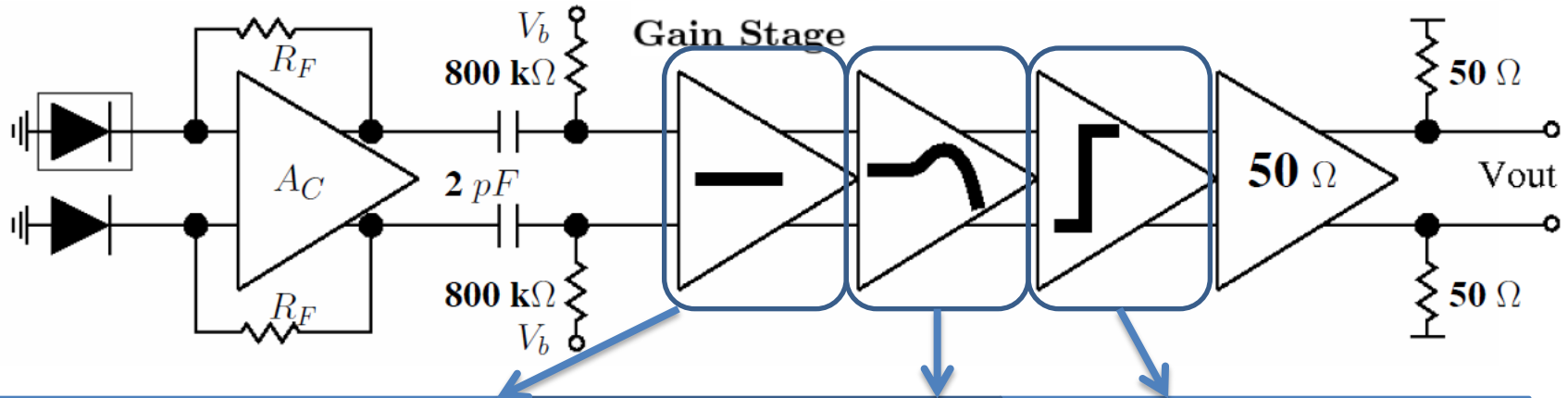


AC Coupling



- Converts single-ended signal to fully-differential
- Facilitates the operation of the TIA from a higher supply voltage
 - ⇒ Higher reverse bias applied across the photodetector
 - ⇒ Increased responsivity approximately 60%

Equalization + Limiting Amplifier

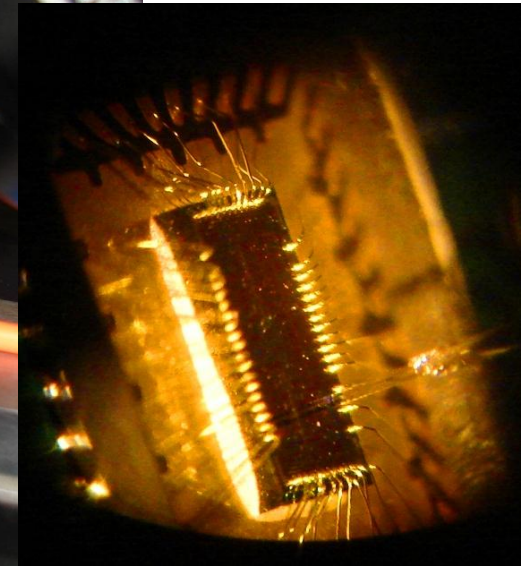
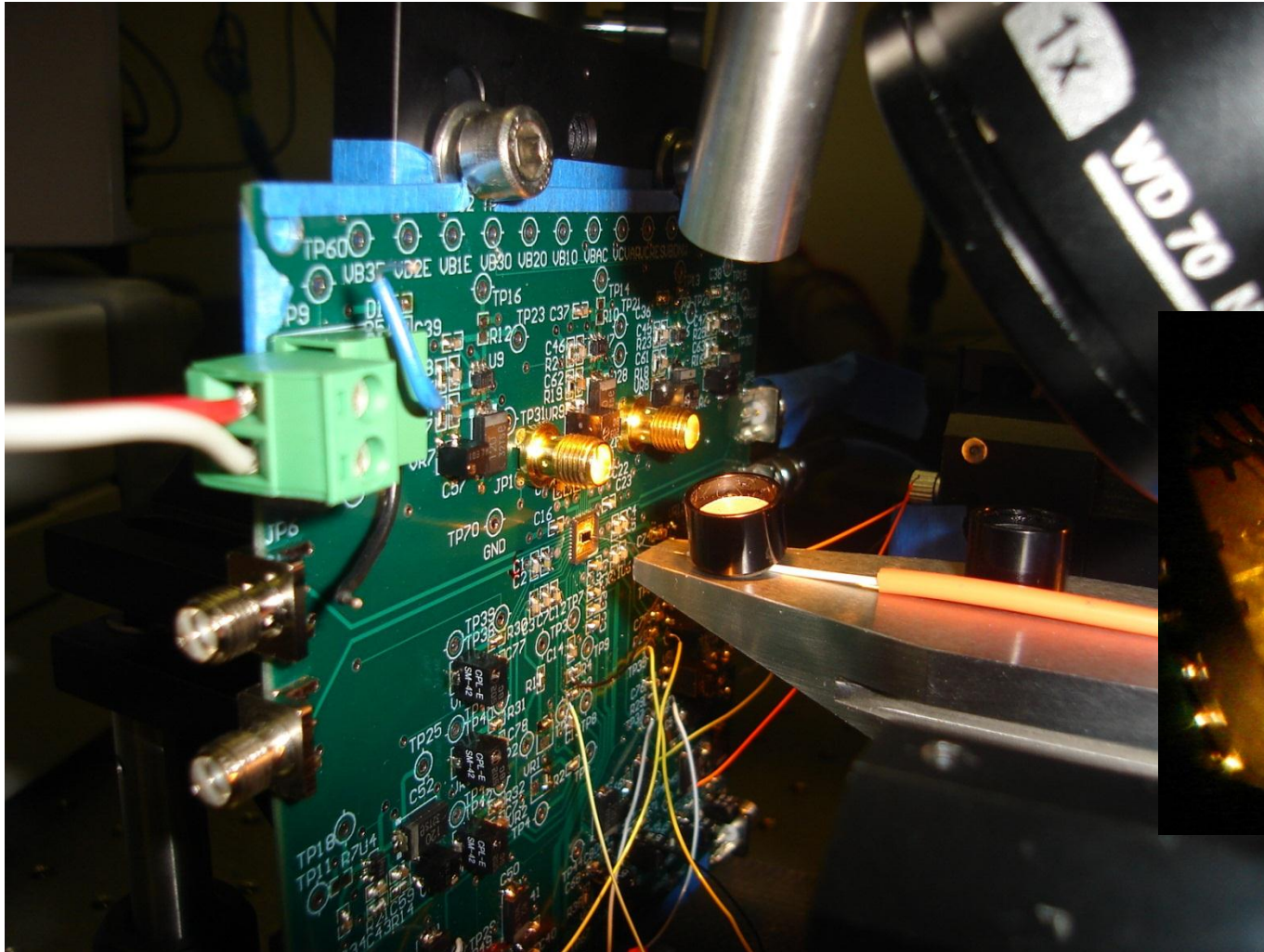


Power Breakdown
(Total 115mW)



- TIA
- Diff. Amp.
- Eq
- LA

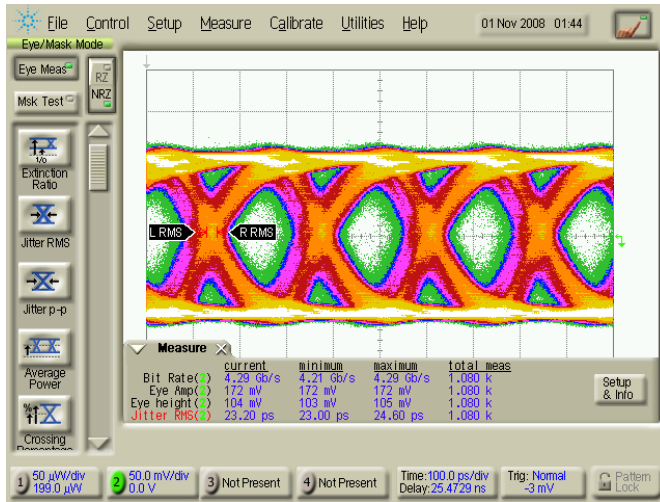
Optical Alignment in Measurements



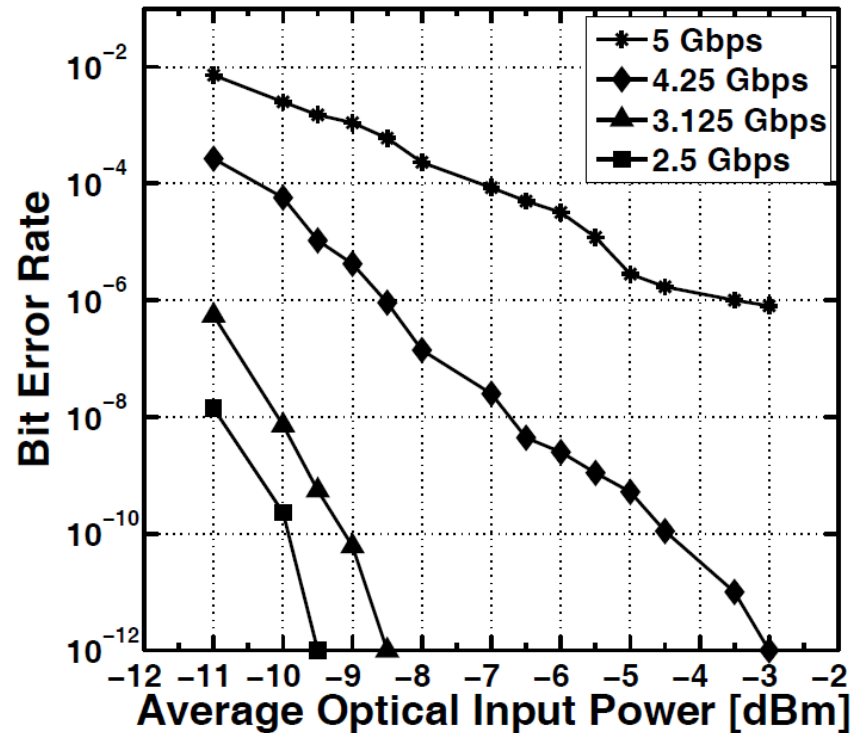
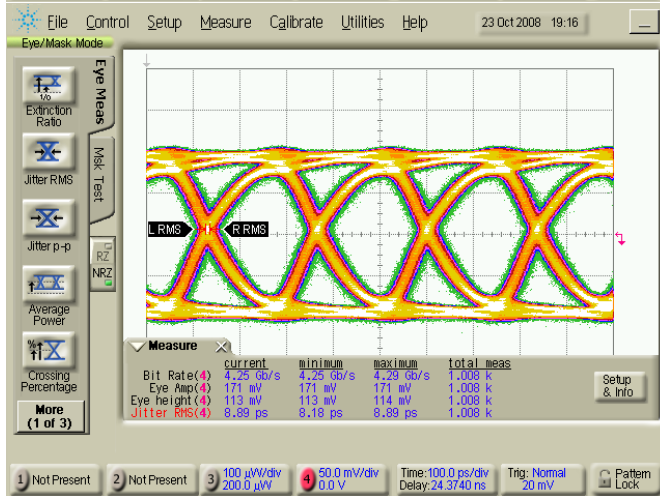
Measurement Results

At 4.25 Gbps

Without equalization



With equalization

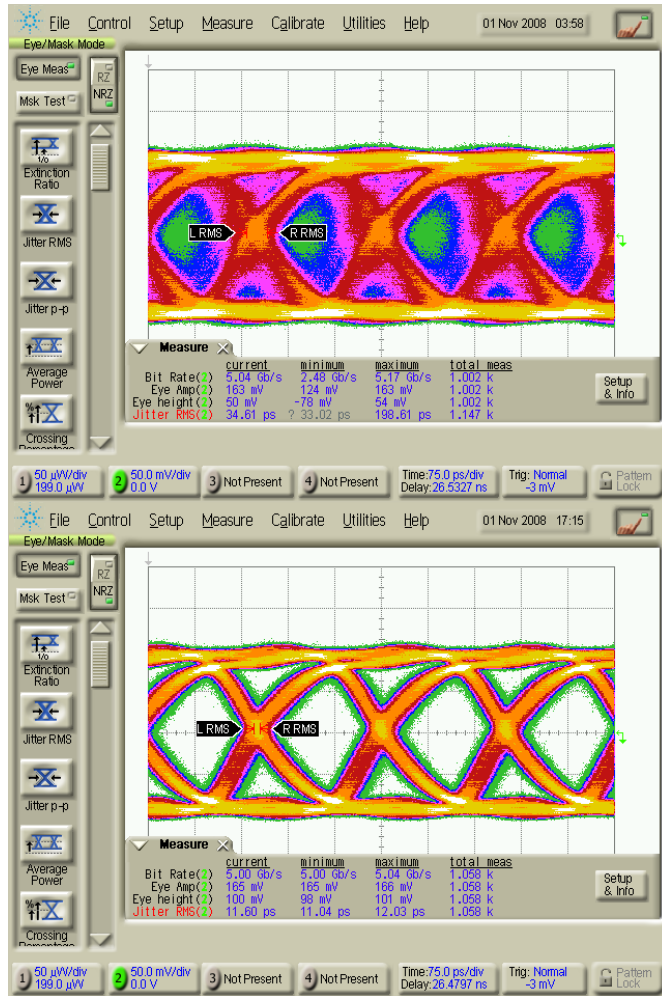


BW-limited at 5 Gbps

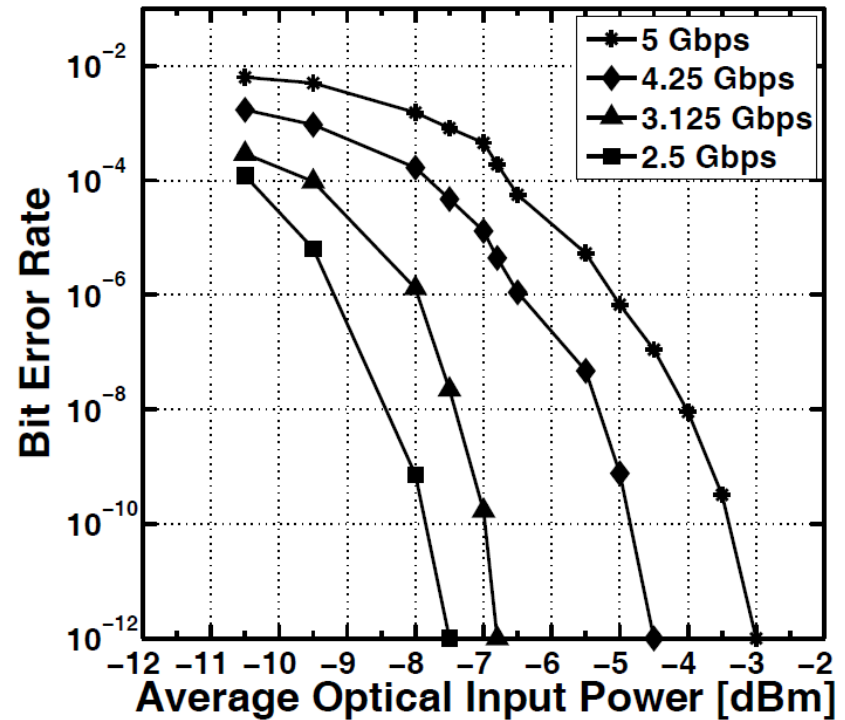
Measurement Results

At 5 Gbps

Without equalization



With equalization

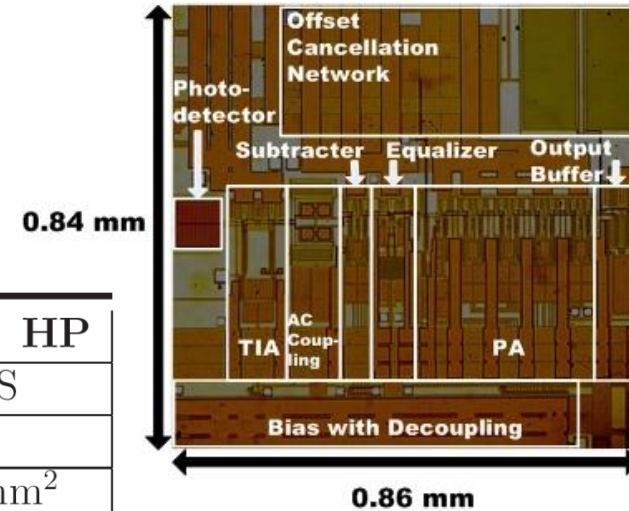


Increased current consumption
in the TIA

⇒ Noise limited at 5 Gbps

Measurement Summary

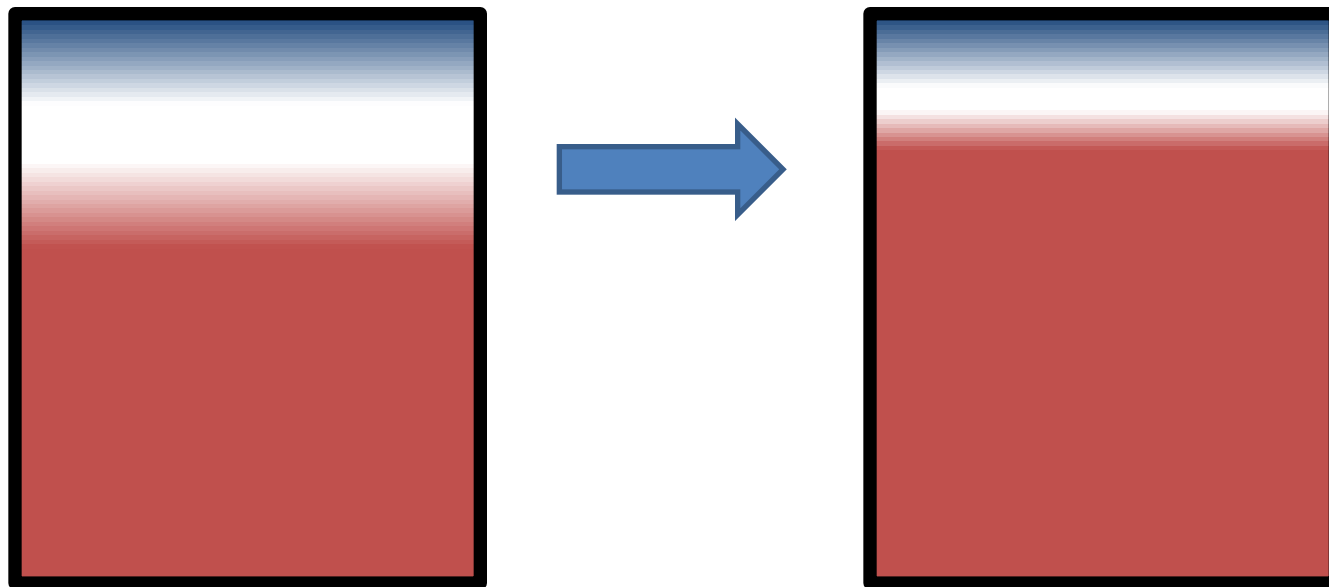
	LP	HP
Technology	0.18- μm CMOS	
Supply voltages	3.3 V, 1.8 V	
Total chip area	$1.5 \times 2.8 = 4.2 \text{ mm}^2$	
Core area of optical receiver front-end	$0.86 \times 0.84 = 0.72 \text{ mm}^2$	
Optical wavelength	850 nm	
Average input power	-3 dBm	
Highest data rate with BER less than 10^{-12}	4.25 Gbps	5 Gbps
RMS jitter	8.89 ps	11.6 ps
Total power consumption with output buffer	144 mW	183 mW
Power consumption without output buffer	129 mW	168 mW



Outline

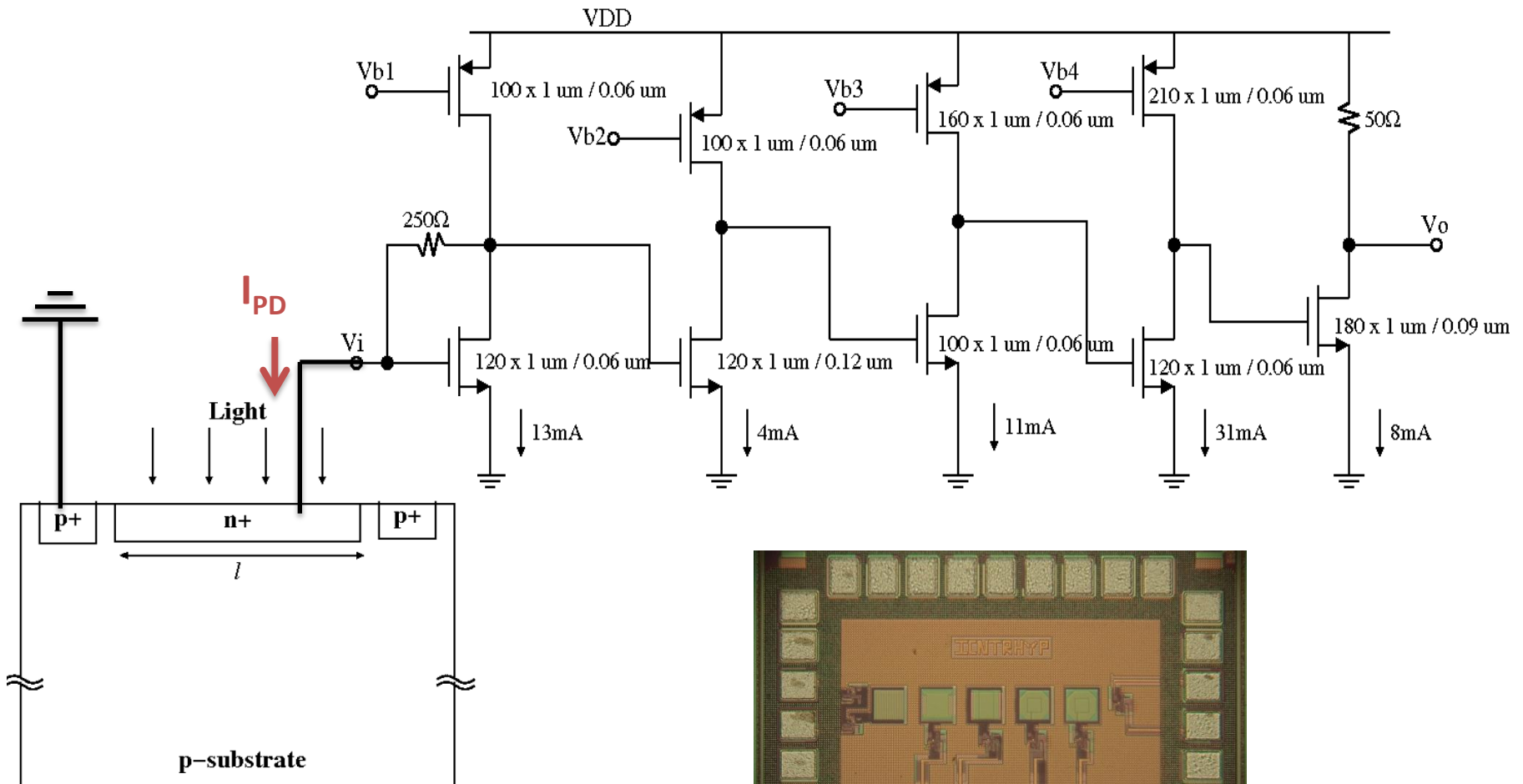
- Introduction
 - Trend towards short-reach optical
 - Trend towards highly integrated transceivers
- Tutorial on High-speed CMOS photodetection
 - Optical properties of silicon
 - Standard CMOS photodetectors
 - Diffusion-shielded photodetectors
 - Spatially modulated light detectors
- Equalization to improve CMOS photodetectors
 - Analog equalization
 - Decision-Feedback Equalization
- Case study: 0.18 μm CMOS integrated optical receiver
 - SML detector
 - Analog equalizer
- **Photodetectors in nanoscale CMOS technologies**
 - **Experimental results from a 65 nm process**

Impact of Technology Scaling

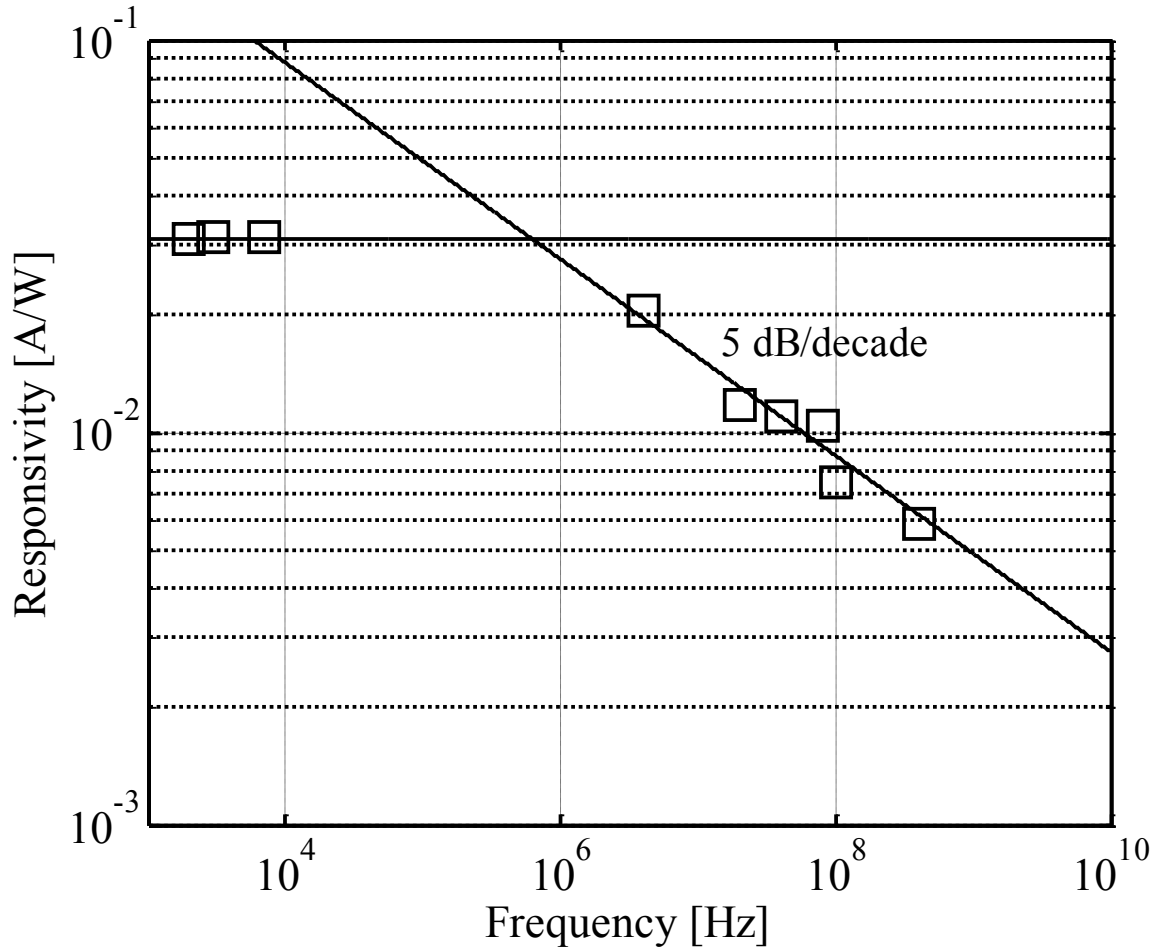


- ✗ Lower supply voltages \Rightarrow lower reverse bias voltages available ?
- ✗ Thinner depletion regions \Rightarrow less drift, more diffusion current, increased C_{pD} ?
- ✗ More complex dielectric stack \Rightarrow reduced light transmission
- ✓ Smaller metallization and contacts admits more light into the silicon
- ✓ “Standard” nanoscale processes provide many different materials, junctions
- ✓ Higher TIA bandwidth
- ✓ Lower power limiting amp, CDR, etc.
- ✓ More advanced signal processing solutions

Example: 65nm CMOS Photodetector



Example: 65nm CMOS Photodetector



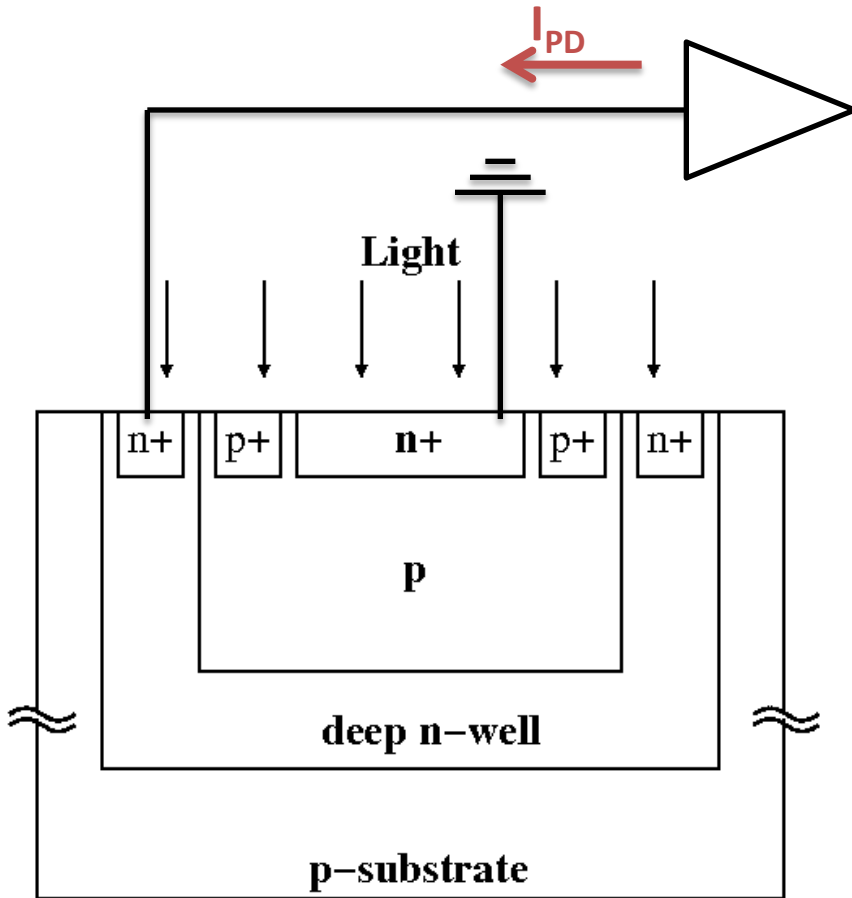
n+/p-epi photodetector
670 mV reverse bias

3-dB bandwidth of 2.5 MHz
20-dB bandwidth \approx 6.3 GHz

DC responsivity = 0.03 A/W
c.f. \approx 0.3 A/W typical
in 0.18 μ m CMOS

- Shorter carrier lifetime?
- Reflection in dielectric stack?

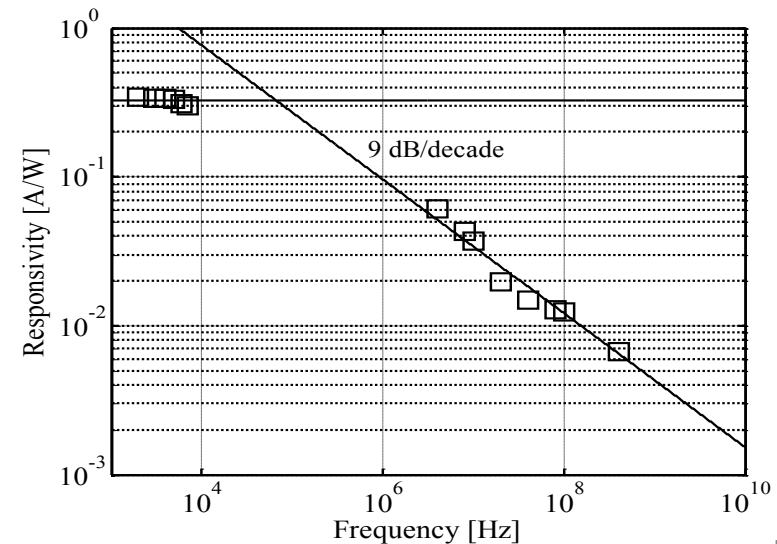
Phototransistor Experiment



- “Base” is left floating; base current is provided by photo-generated carriers
- The photocurrent observed at the “collector” is amplified by transistor action

65-nm CMOS measurements:

- > 0.3 A/W observed at low frequencies
- BUT 3-dB bandwidth of only 0.15 MHz



Conclusions

- There are applications at 850nm or shorter wavelengths where a high level of integration is more important than very high sensitivity
- A combination of
 - Clever use of existing CMOS process features
 - Signal processing circuitryhave so far permitted performance in the range of 5 – 8.5 Gb/s @ -5 – 0 dBm input and 50 – 150 mW (better if very high supply voltages are permitted)
- Future progress:
 - Integration in nanoscale CMOS
 - Power reductions, speed improvements, sensitivity improvements
 - Demonstrable robustness in manufacture and test